



NDE with SQUIDS

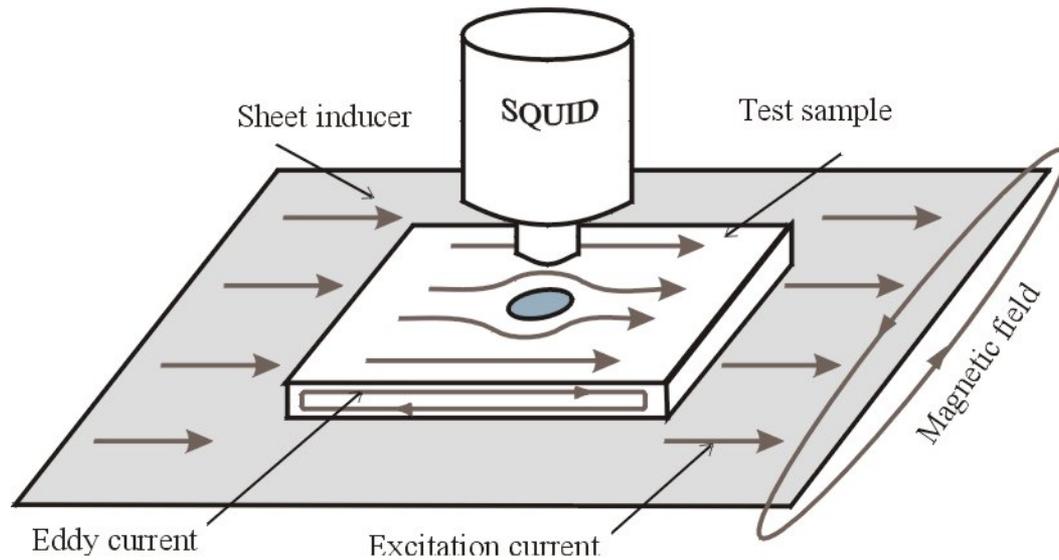
*Sheet Inducers and Depth-Selective,
Oriented Current Imaging*

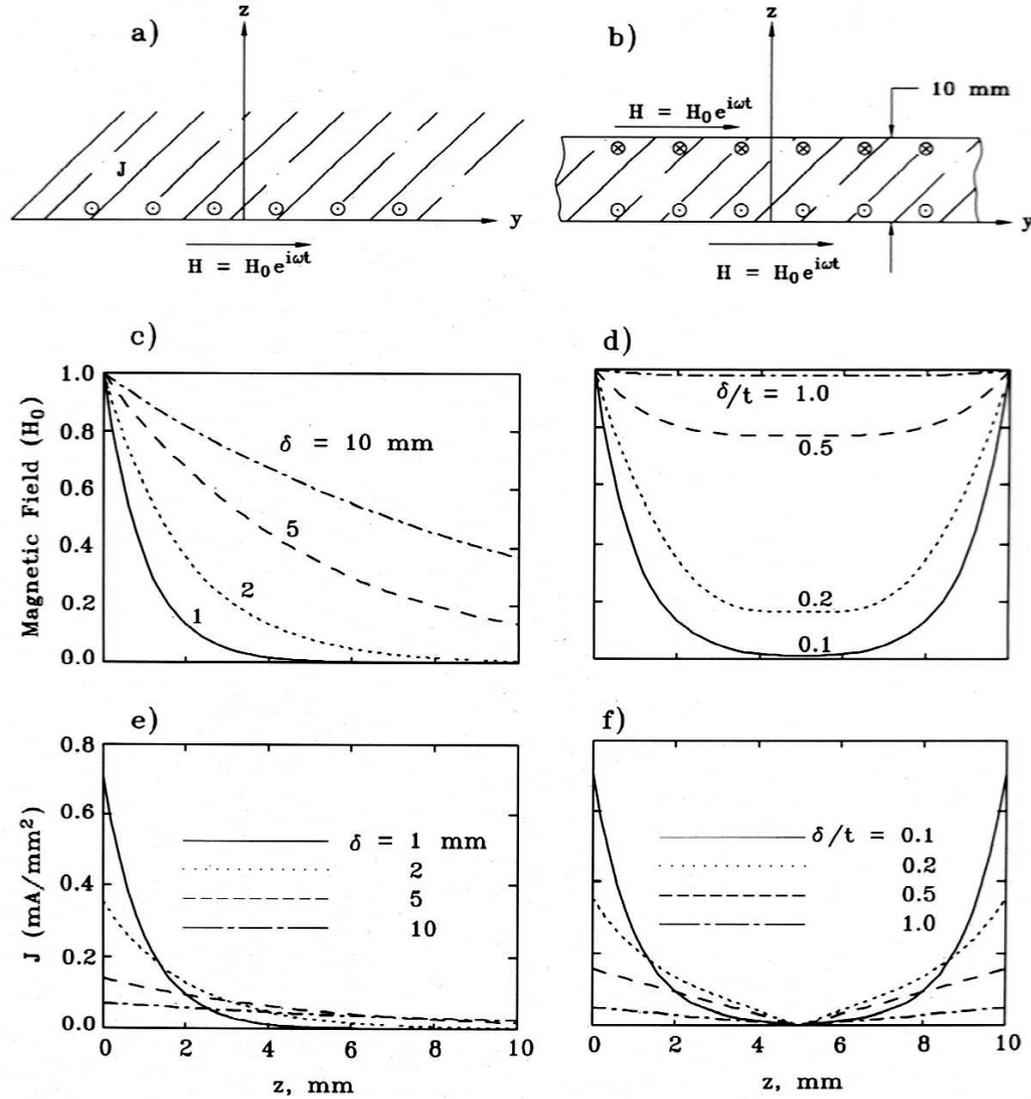
Yu Pei Ma and John Wikswo

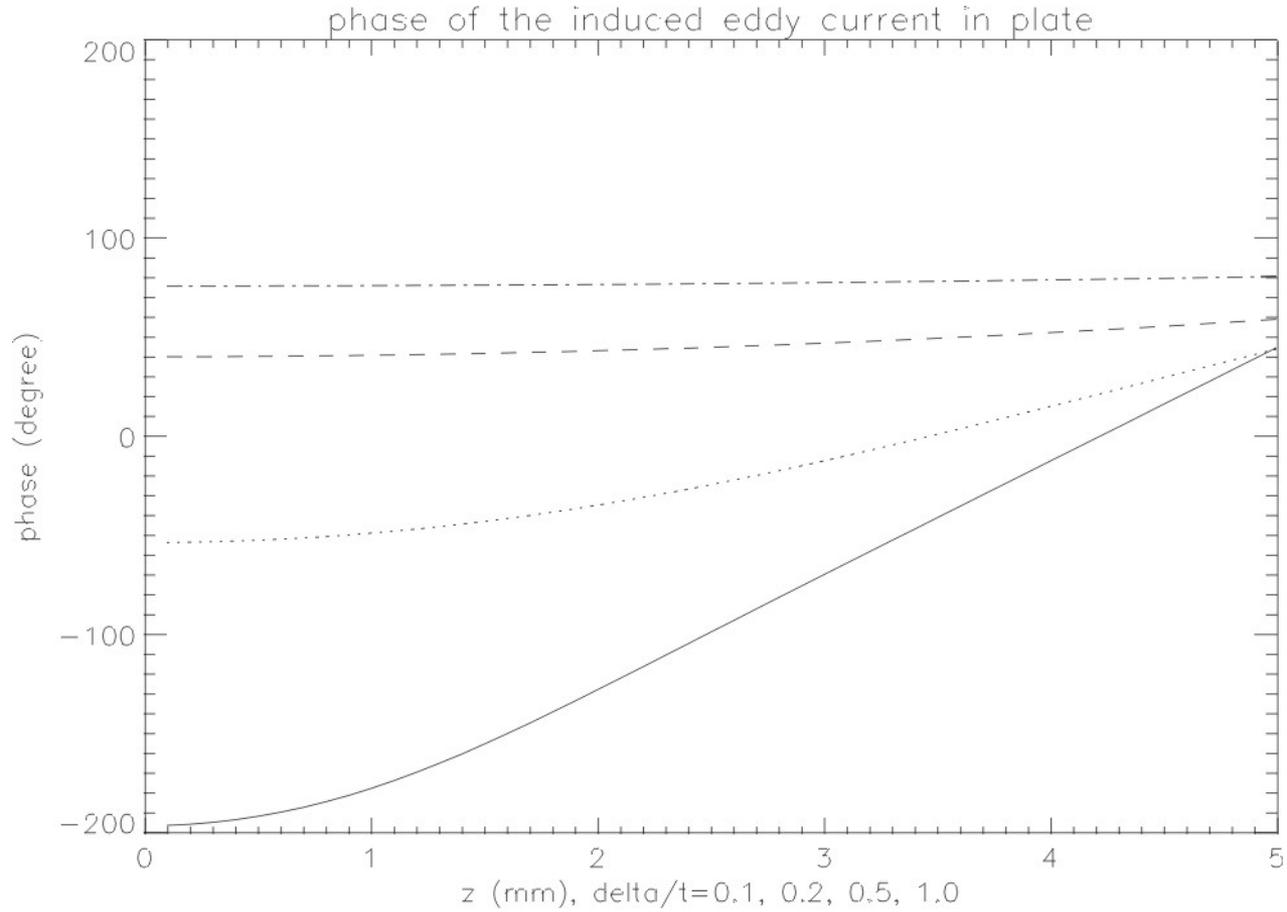
Electromagnetics Laboratory

Department of Physics and Astronomy

Vanderbilt University, Nashville, TN 37235

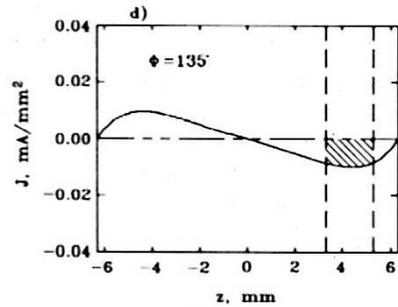
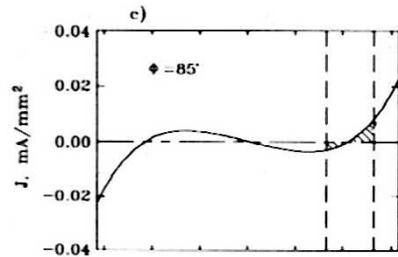
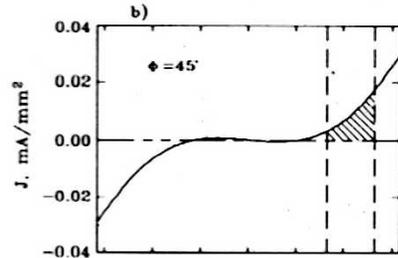
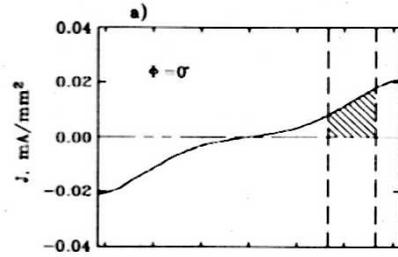




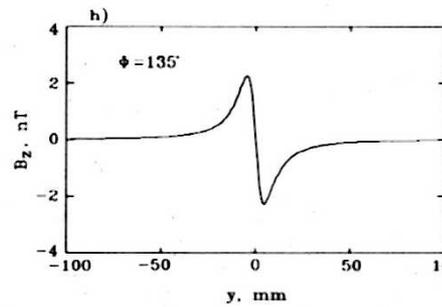
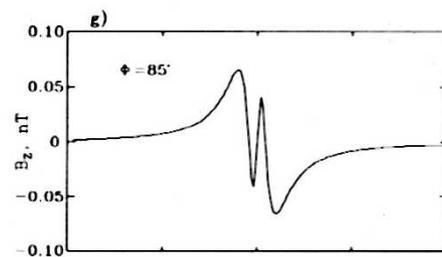
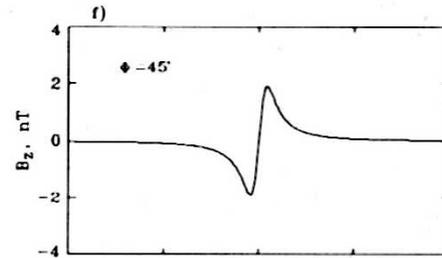
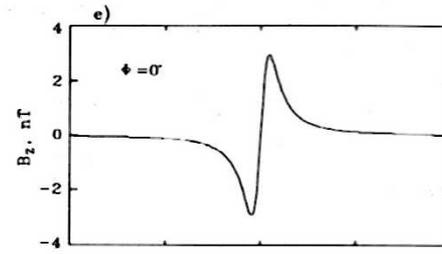




Calculated current distribution



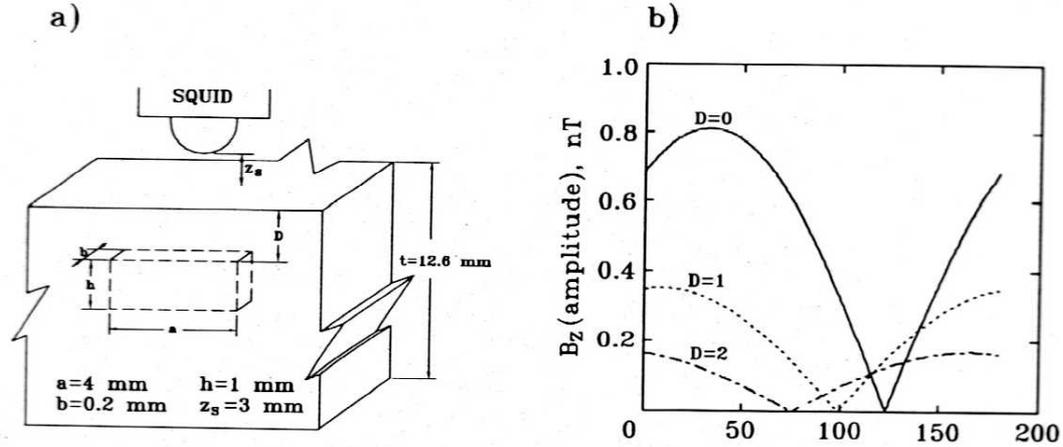
Calculated magnetic signal



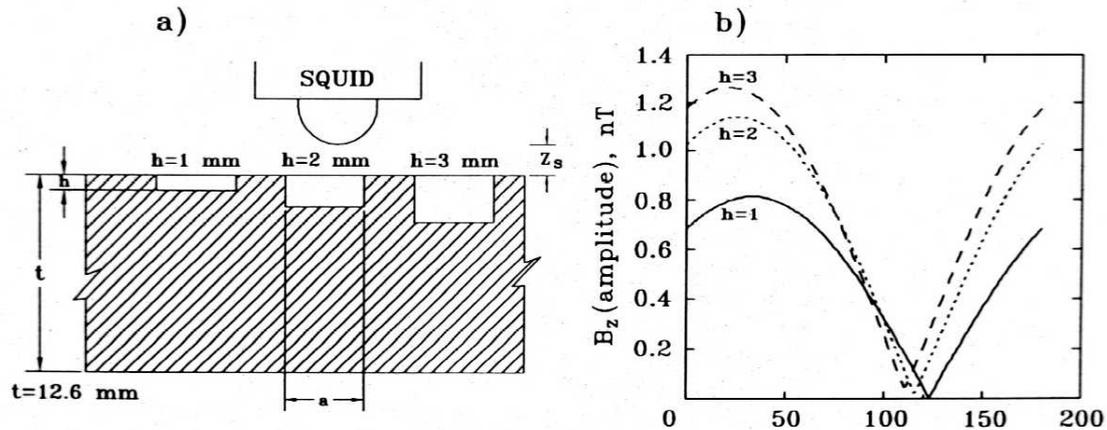
$\delta = 2.4\text{mm}$, $t = 12.6\text{mm}$ Void: $\phi 8 \times 3\text{mm}$ at 1mm below the surface



- Squared maximum value of the signal vs depth of flaw



- Squared maximum value of the signal vs size of flaw





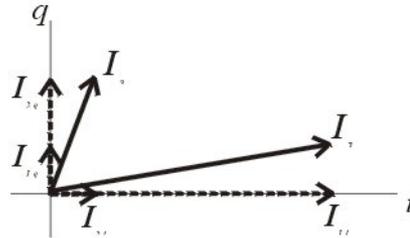
DEPTH - SELECTIVE TECHNIQUE



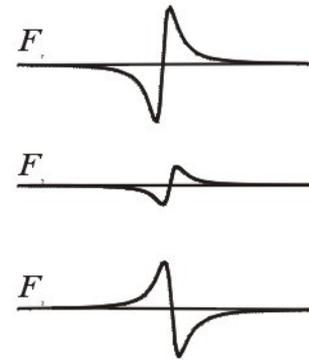
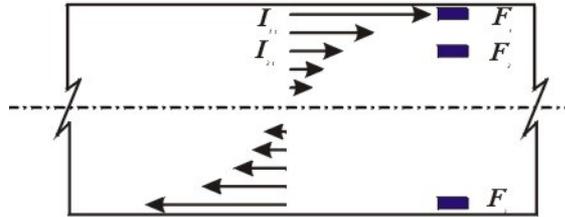
ELECTROMAGNETICS LABORATORY

DEPARTMENT OF PHYSICS AND ASTRONOMY, VANDERBILT UNIVERSITY

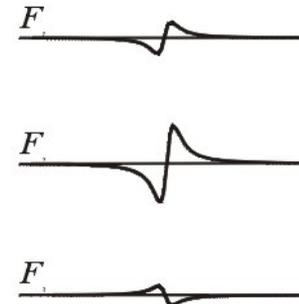
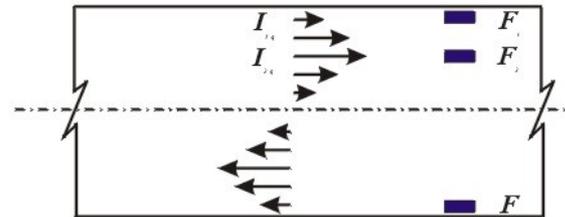
(a) Current vector



(b) In-phase component (phase 0°)



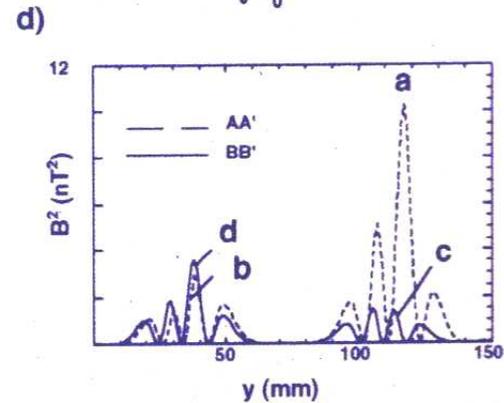
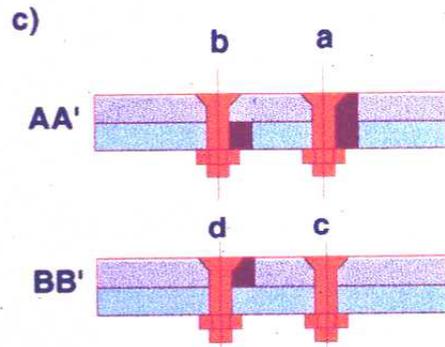
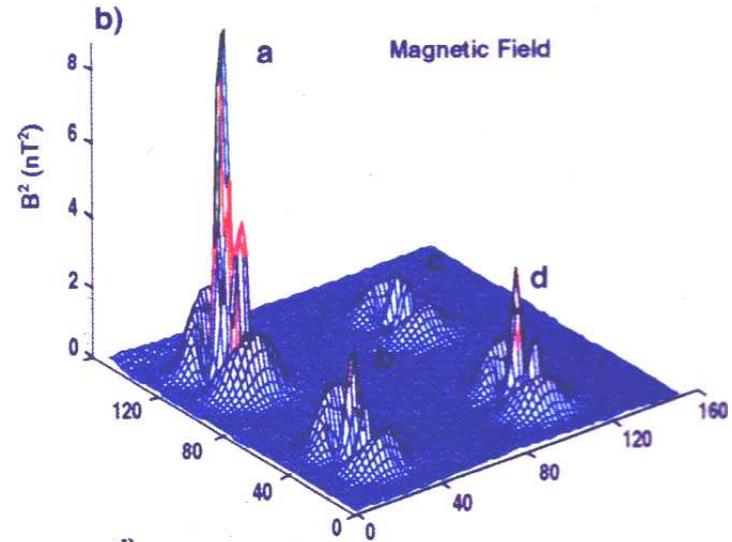
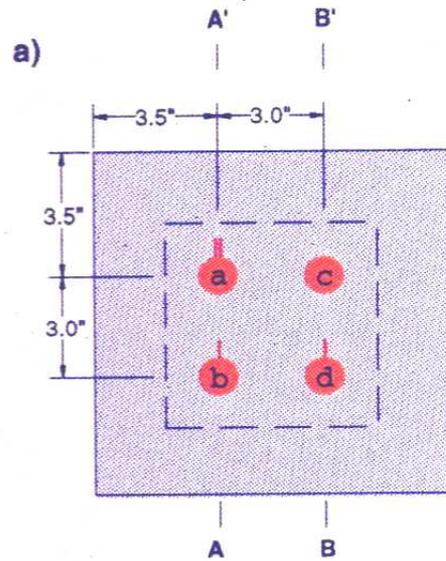
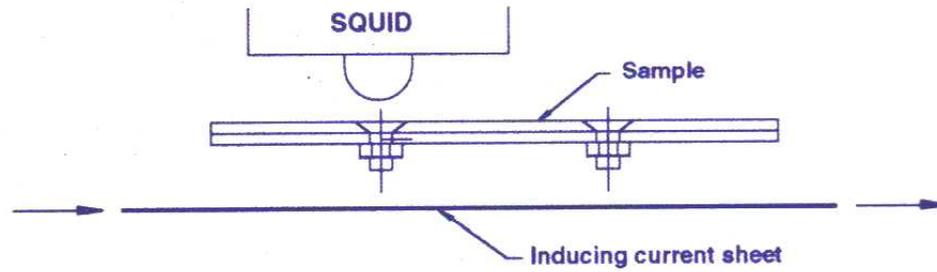
(c) Quadrature component (phase 90°)





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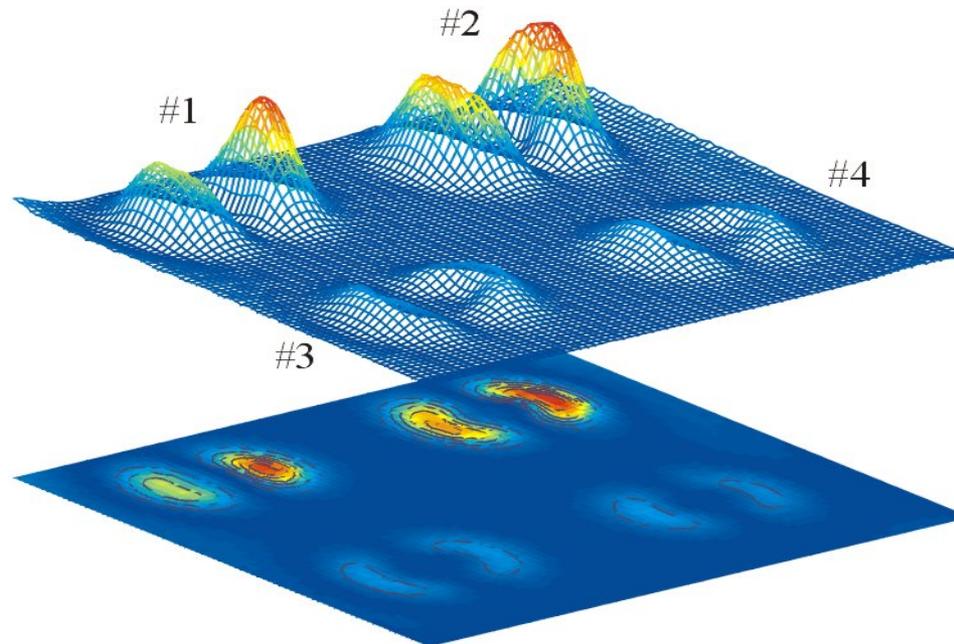
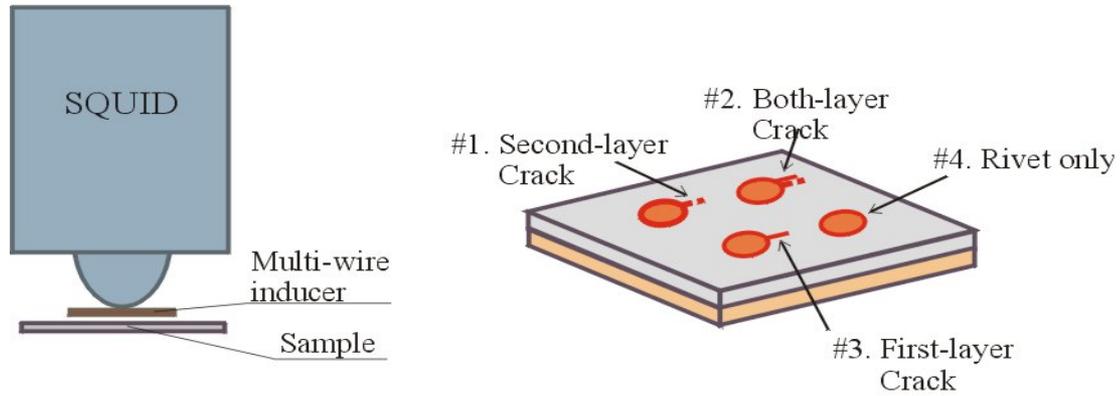
DEPARTMENT

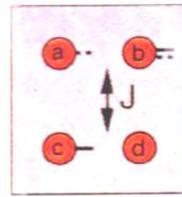




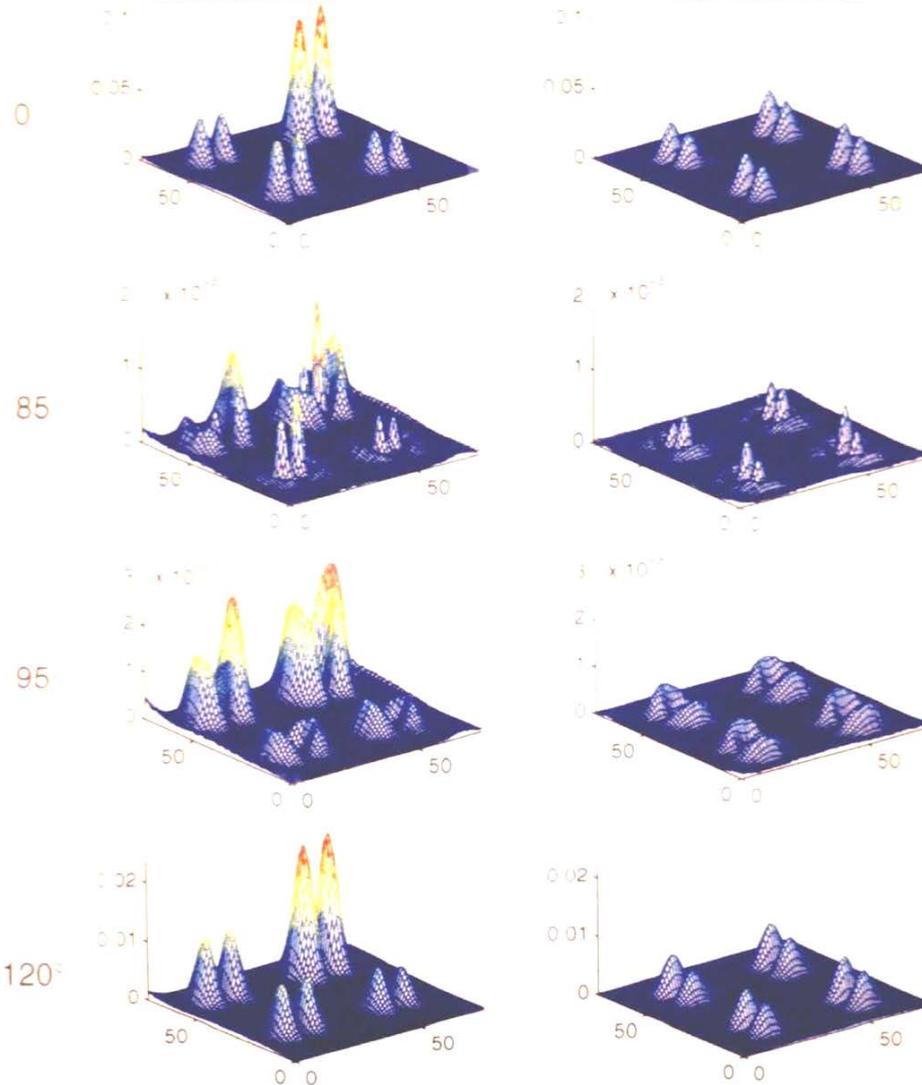
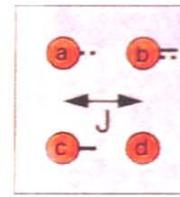
MAGNETIC IMAGE OF CRACKS ADJACENT TO RIVETS

(Using Depth-Selective Technique)





Phase Analysis



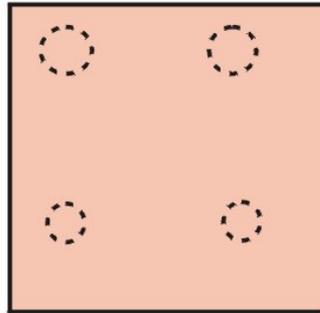


SAMPLE WITH HIDDEN CORROSION (7075-T6)

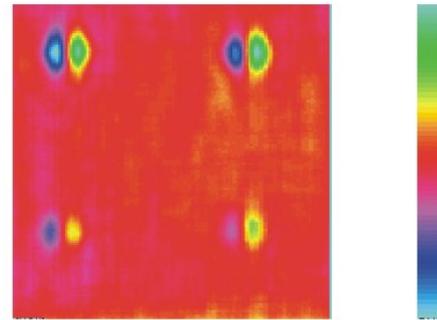
(Two 0.125 inch thick aluminum plates with four sites of corrosion in the second layer)

$f = 210 \text{ Hz}$, Phase = 130°

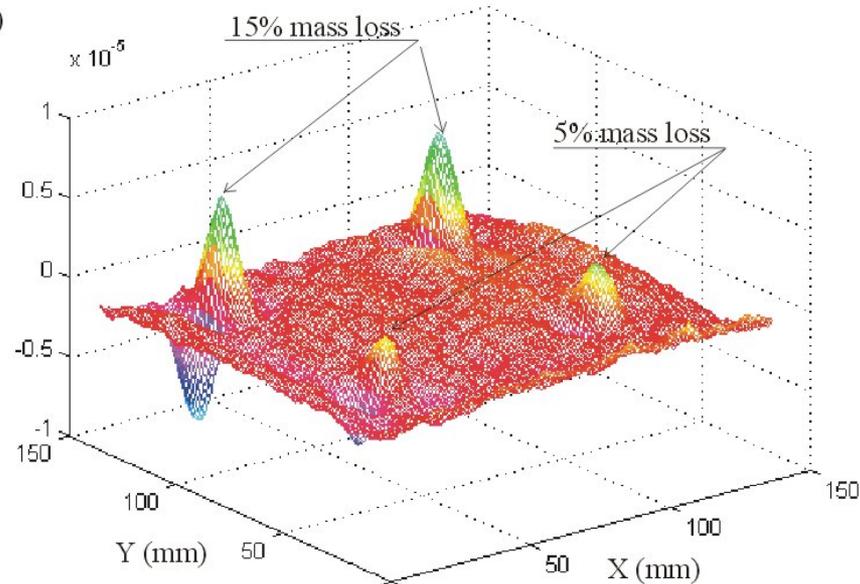
a)



b)



c)

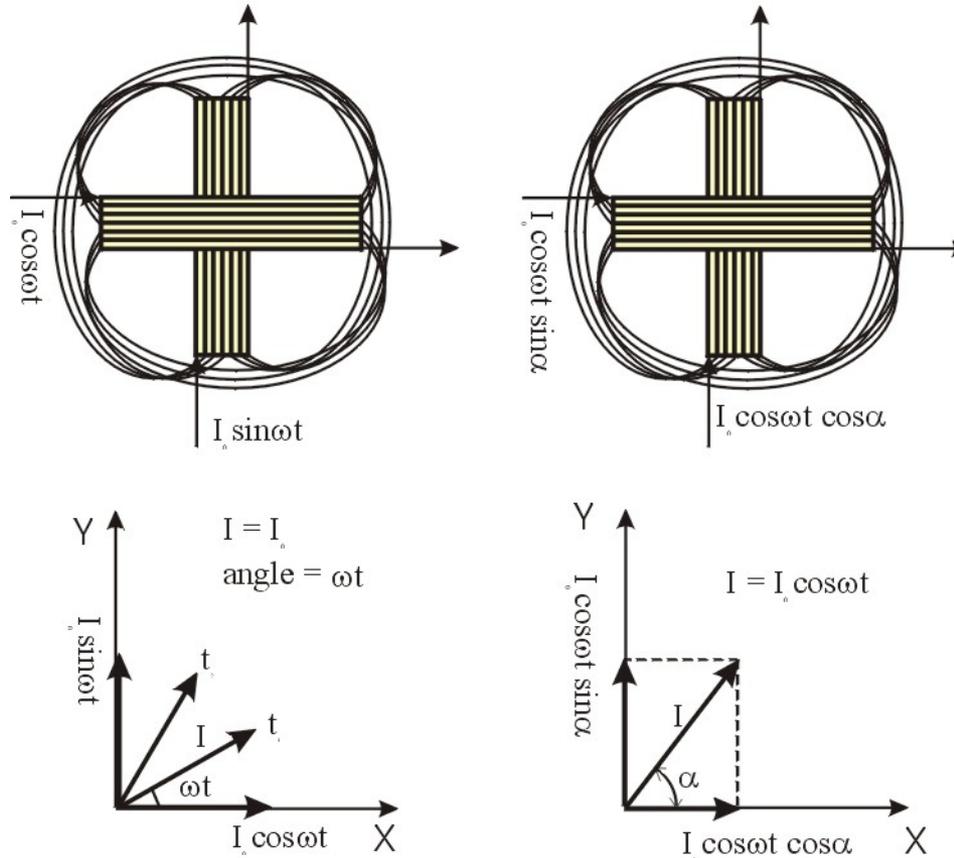


Sample provided by Lockheed,

Inducer with 4 wires



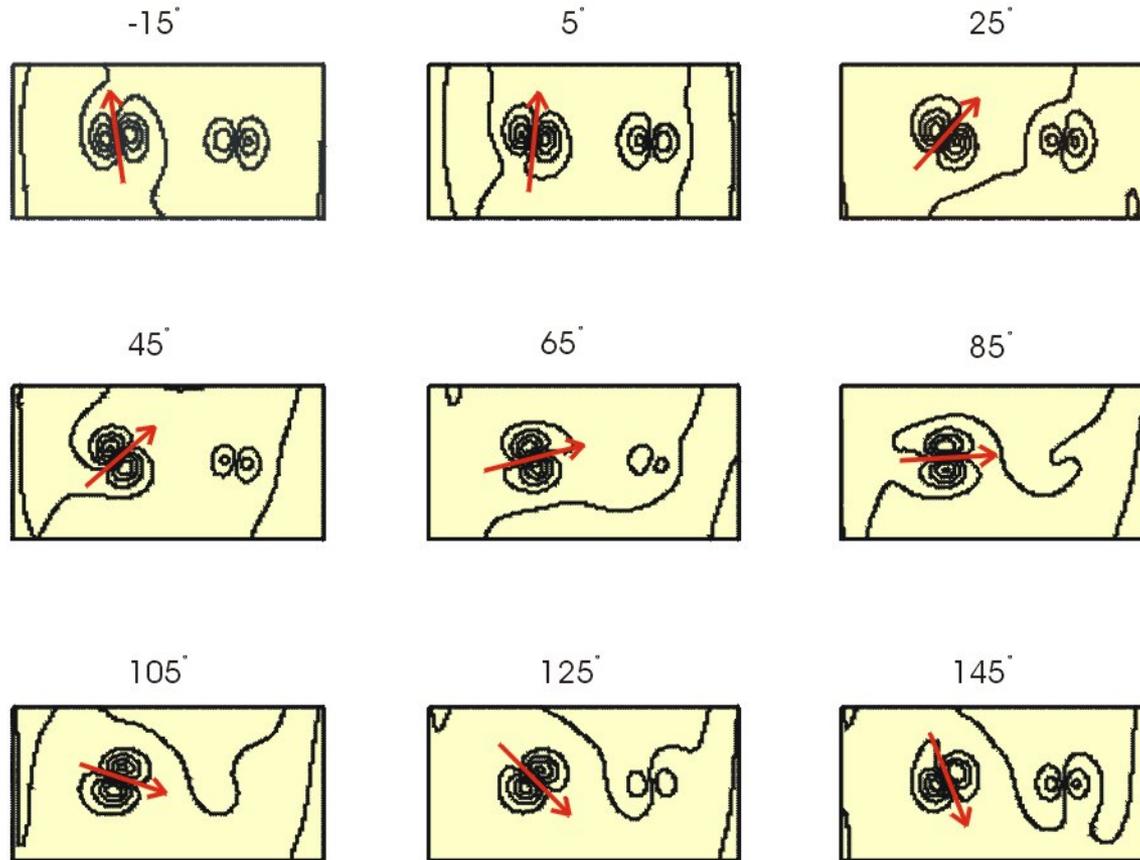
ORTHOGNAL SHEET INDUCER





ROTATING CURRENT

Orthogonal inducer with 90° phase shift.



SAMPLE: 2mm thick aluminum plate.

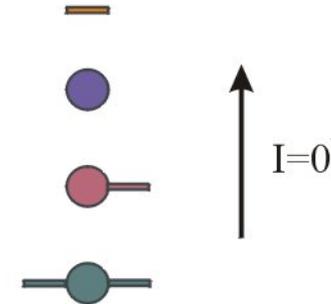
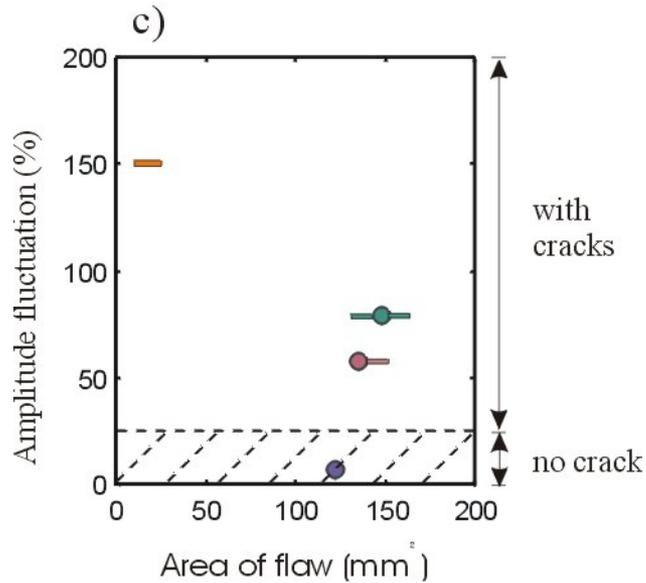
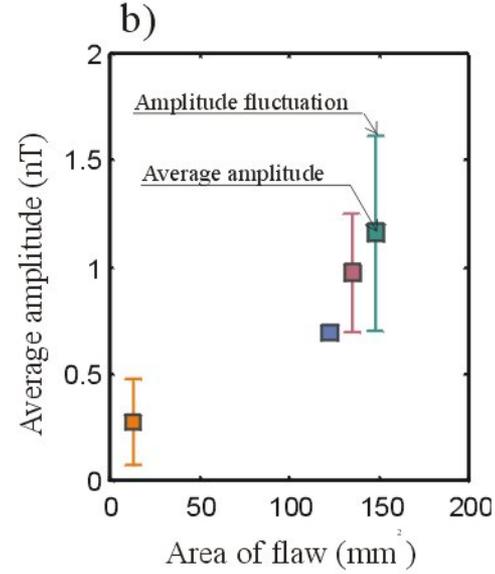
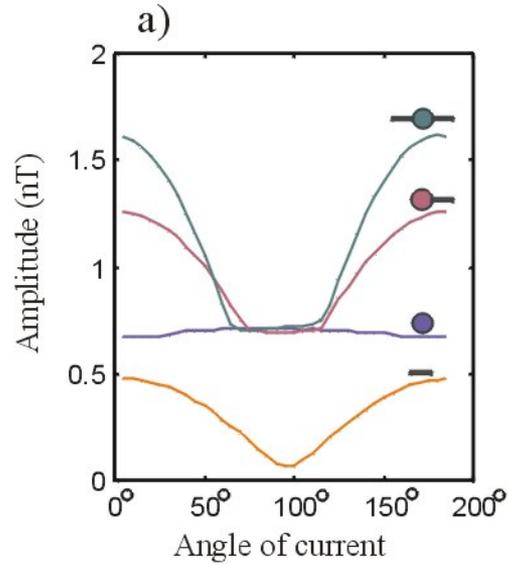




SELF-REFERENCE



SELF REFERENCE FOR CRACKS ADJACENT TO HOLE

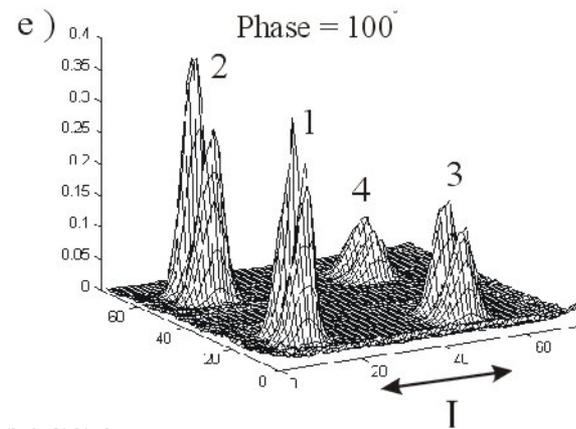
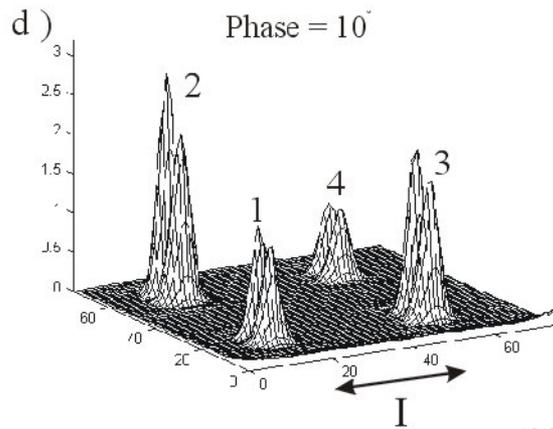
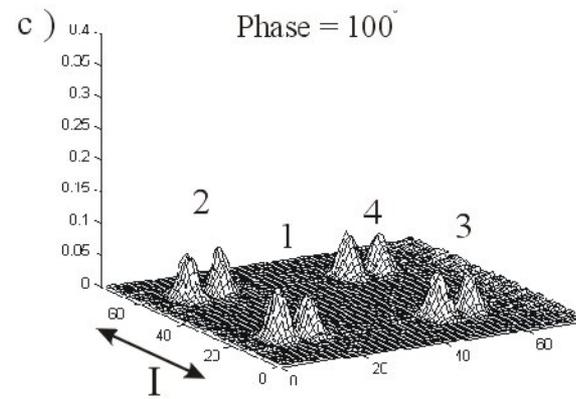
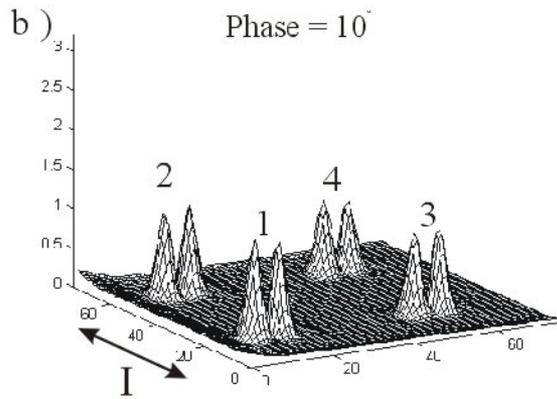
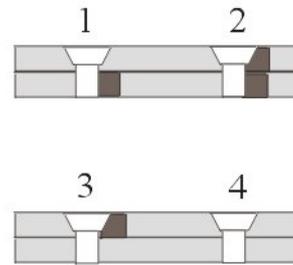
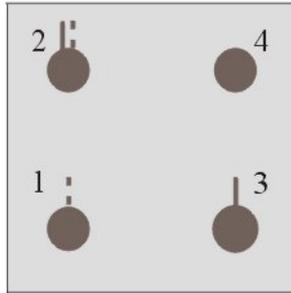




SELF-REFERENCING

and

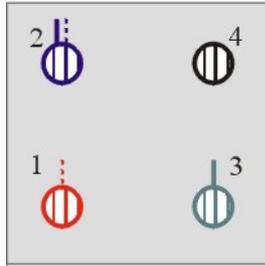
PHASE SELECTION



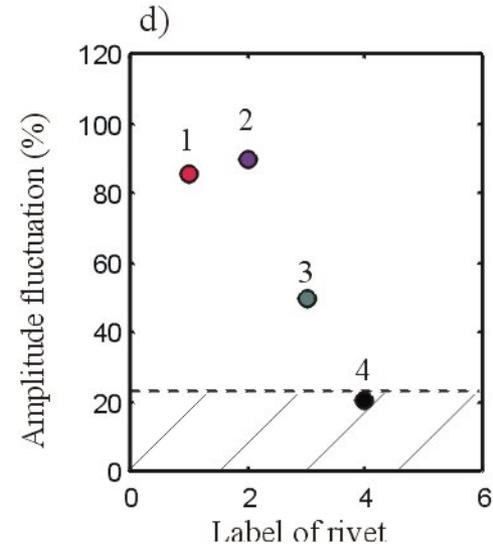
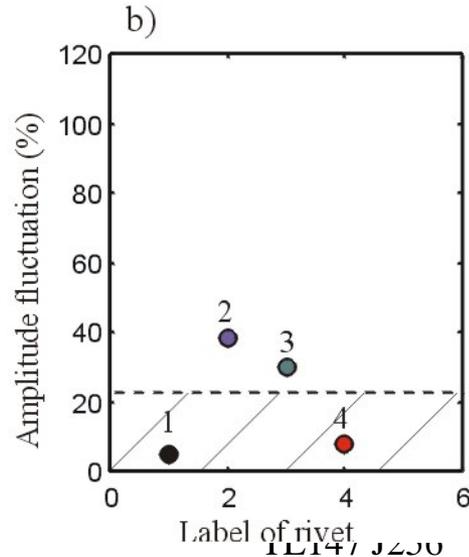
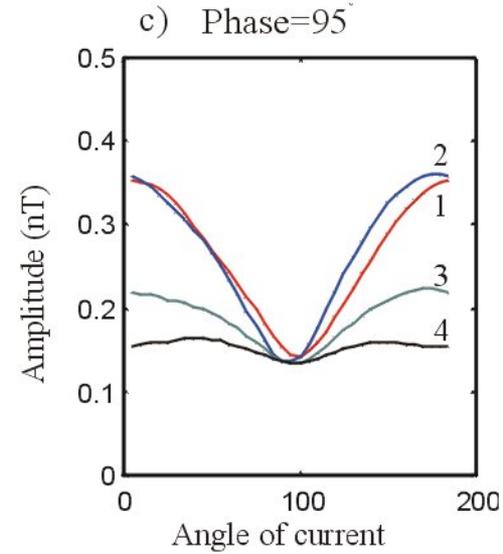
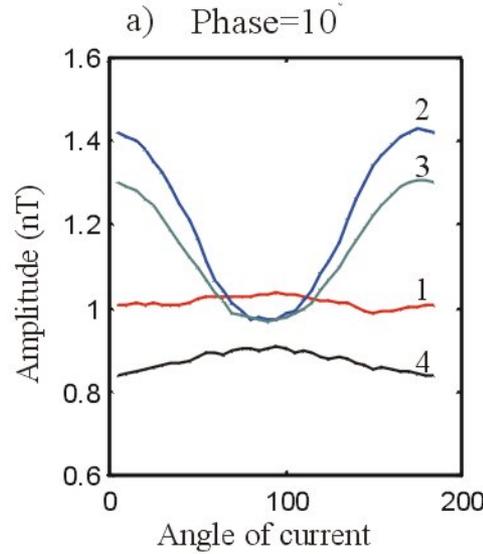


SELF REFERENCE WITH PHASE ANALYSIS

Orthogonal sheet inducer with in-phase currents

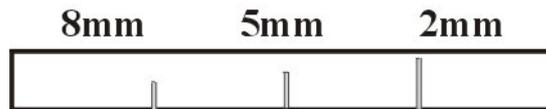
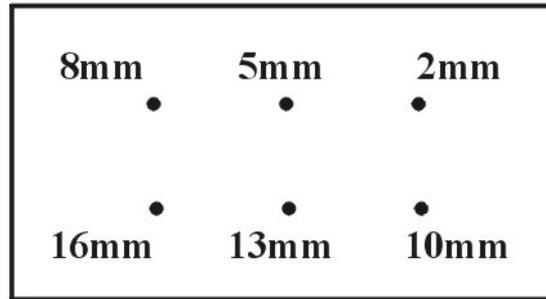


Two layers Al plate with four rivets.





SAMPLE #1 Al 7075-T6
#2 Al A356

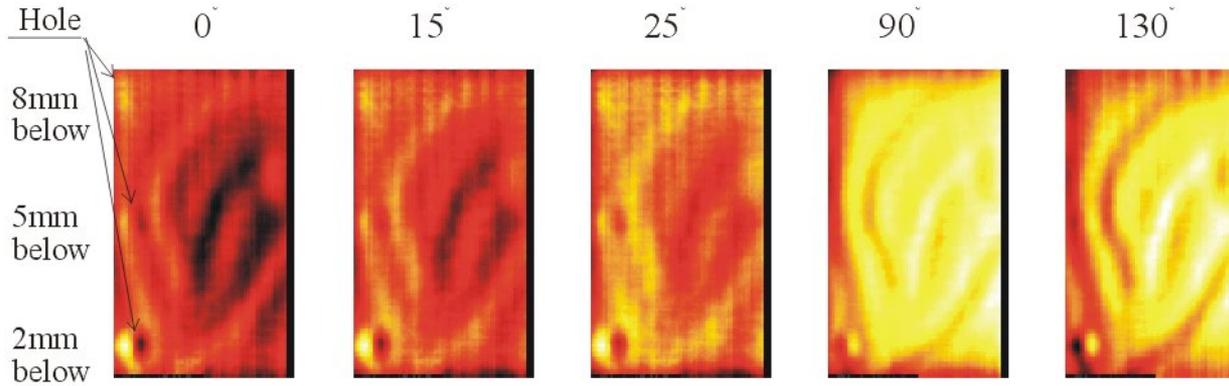


All holes are 1.2 mm diameter.
Samples are provided by Alcoa

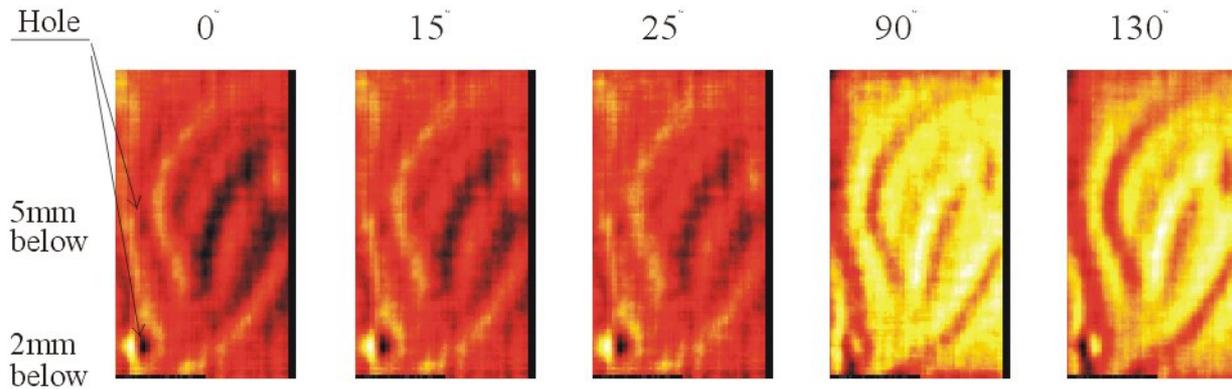


(18 mm aluminum plate with 1.2 mm diameter holes below surface)

$f=170\text{Hz}$

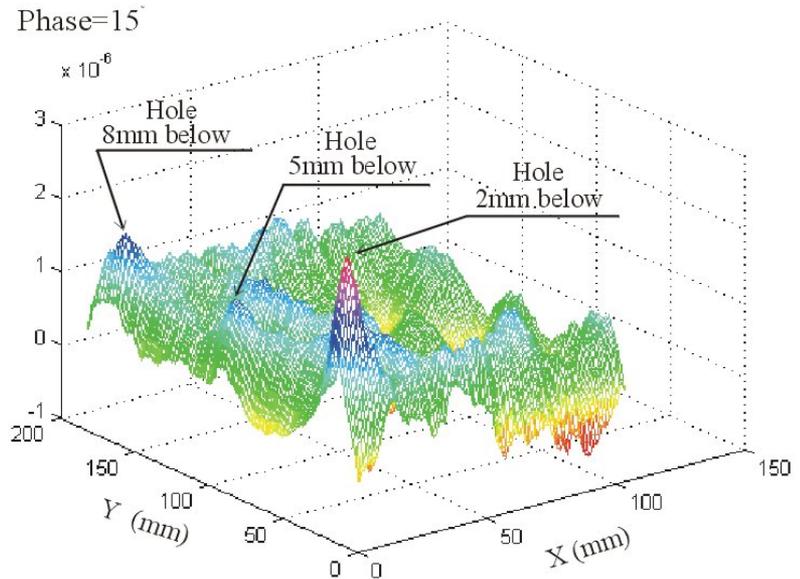
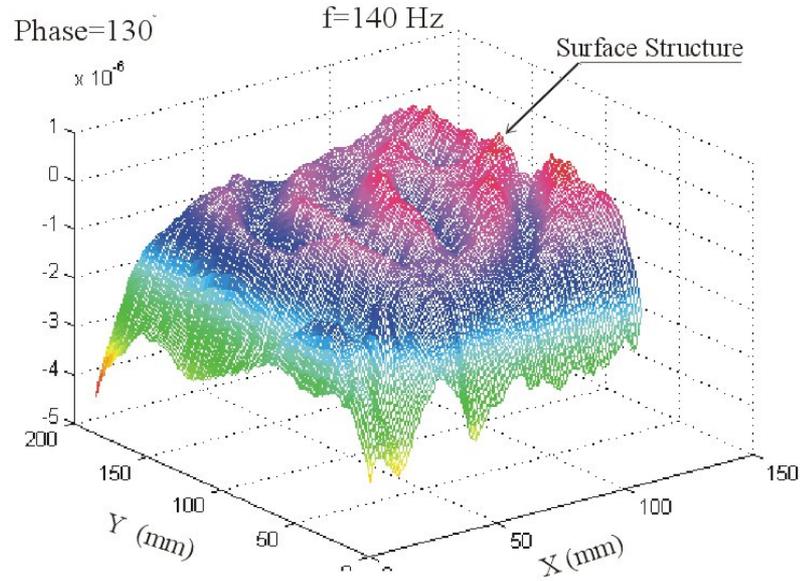


$f=340\text{Hz}$





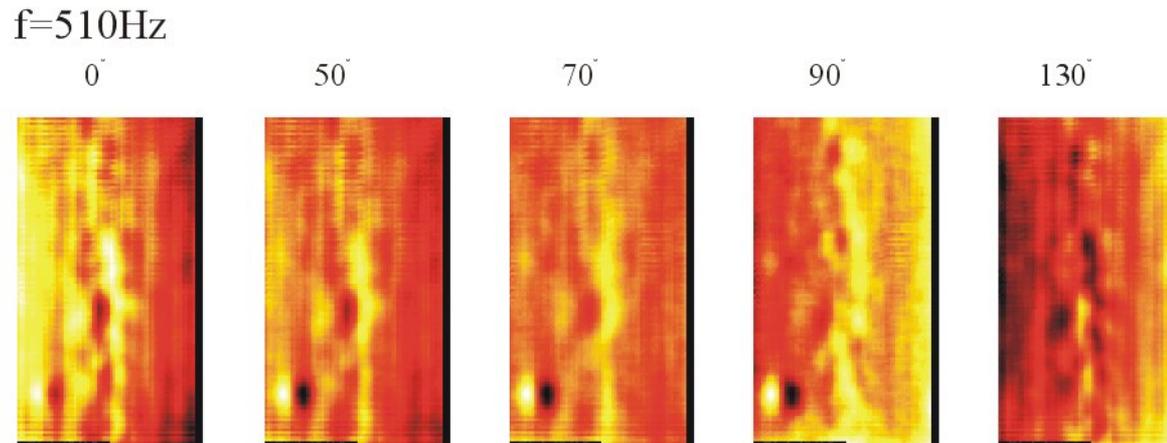
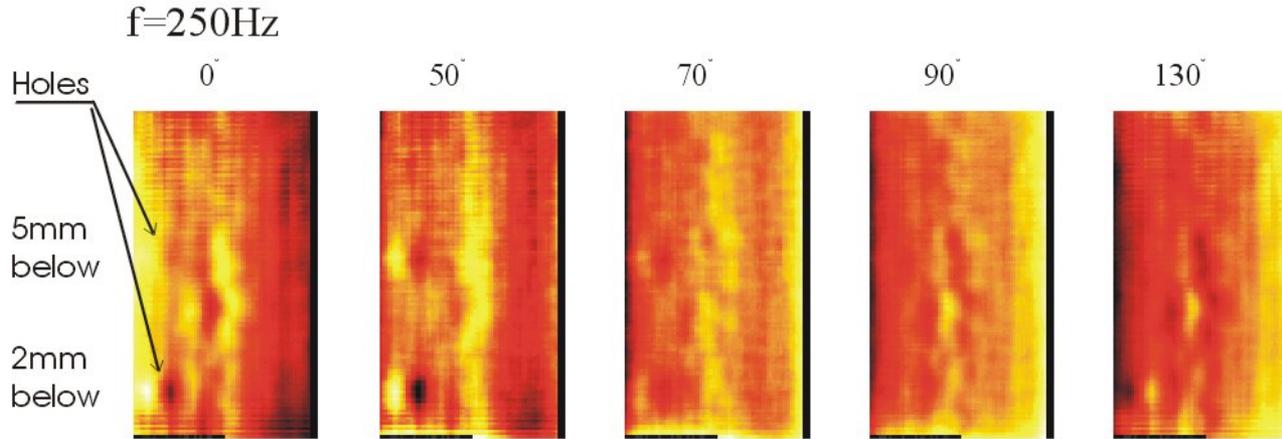
(18 mm aluminum plate with 1.2 mm diameter holes below surface)





SAMPLE #2 (A356-2)

(18 mm aluminum plate with 1.2 mm diameter holes below surface)



Sample provided by Alcoa

Inducer with 4 wires



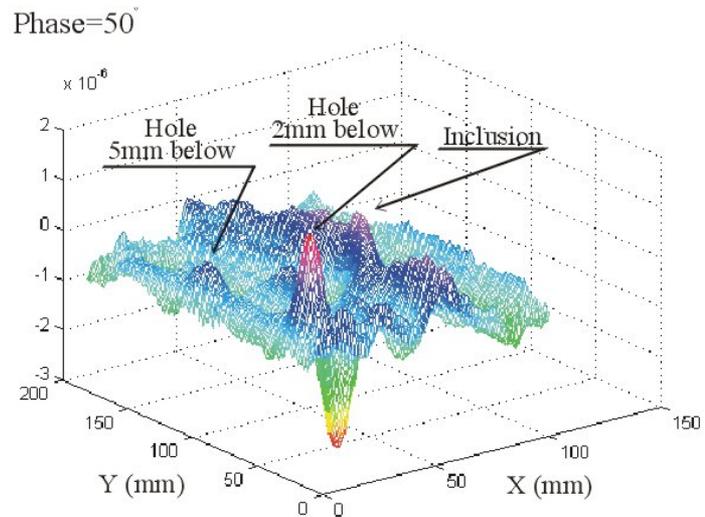
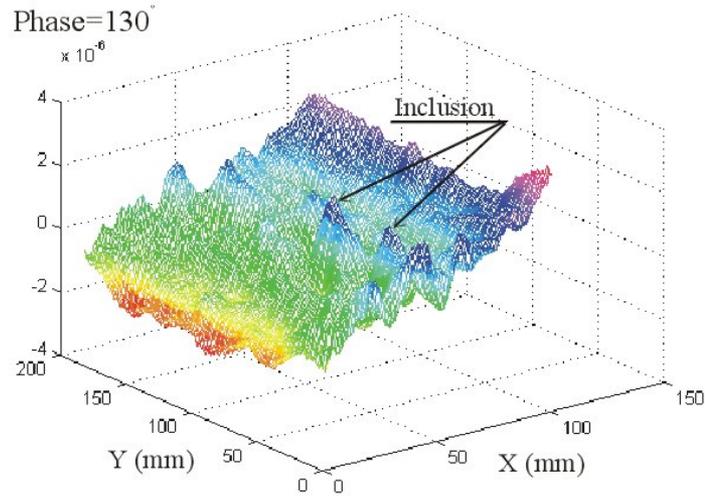
ELECTROMAGNETICS LABORATORY

DEPARTMENT OF PHYSICS AND A

SAMPLE #2 (A356-2)

(18 mm aluminum plate with 1.2 mm diameter holes below surface)

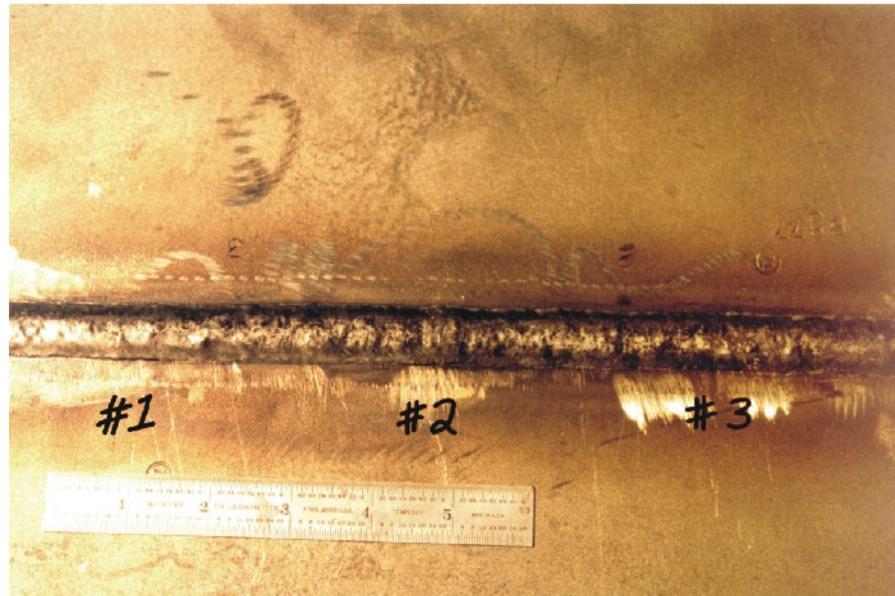
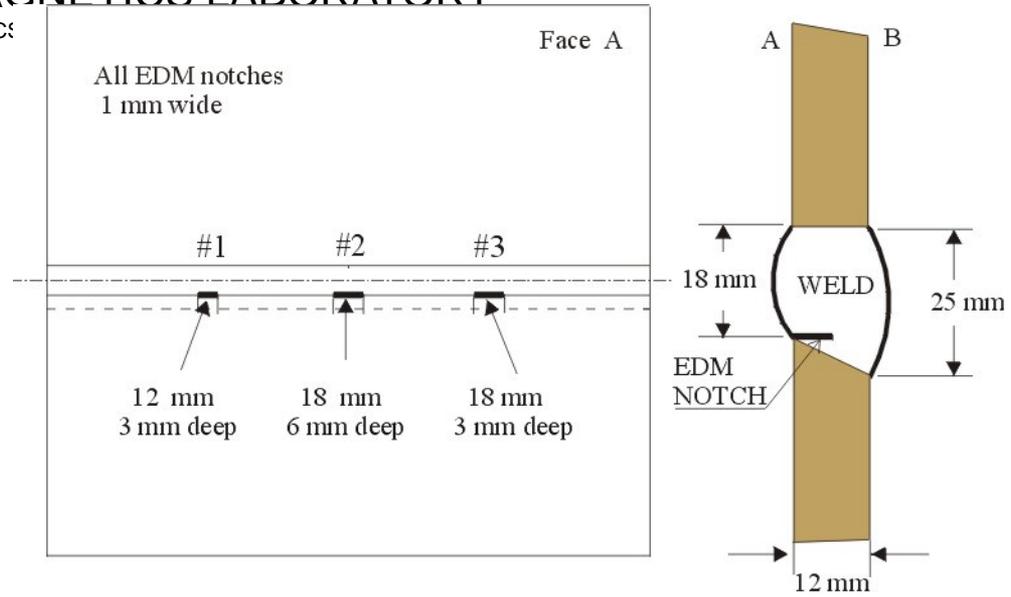
$f=250\text{Hz}$





ELECTROMAGNETICS LABORATORY

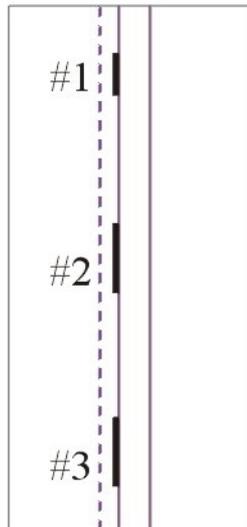
DEPARTMENT OF PHYSICS



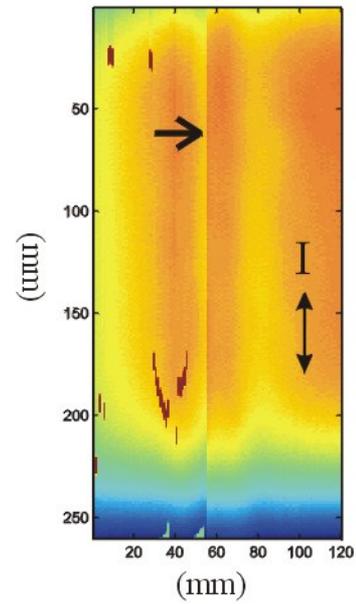
1L147 J250



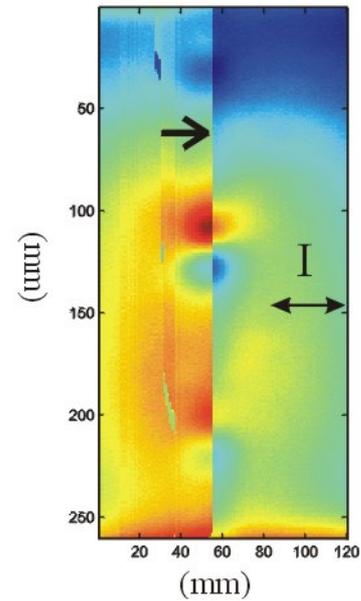
a) Face A



b) Longitudinal current

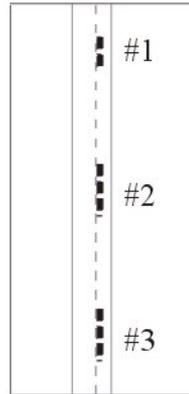


c) Transverse current

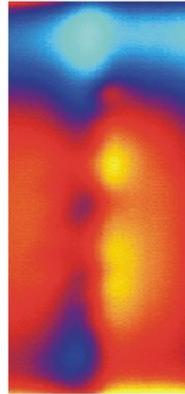




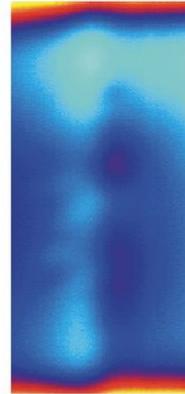
a) Face B



b) Phase 150

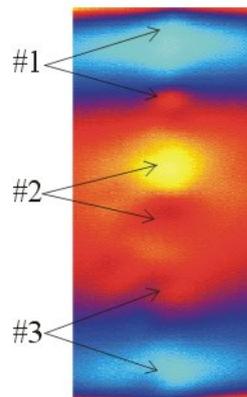


c) Phase 180

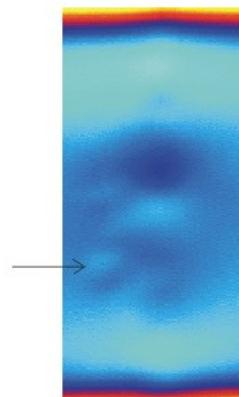


↔
Induced
Current

d) Phase 150

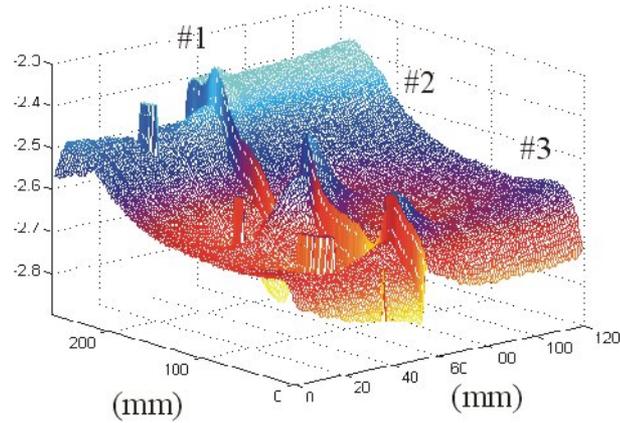


e) Phase 180

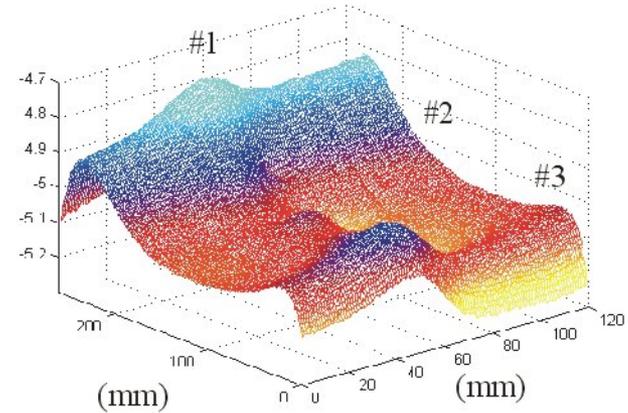




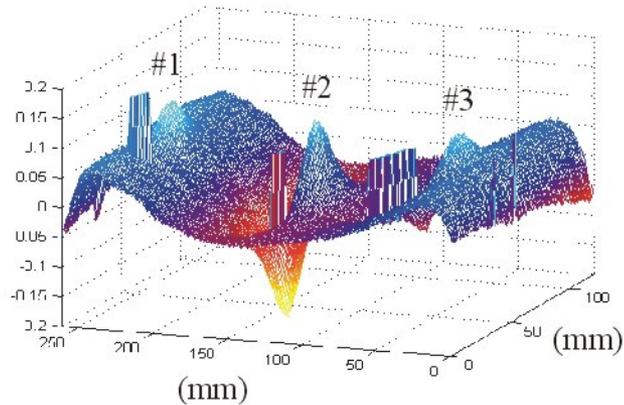
a) Face A with open notches



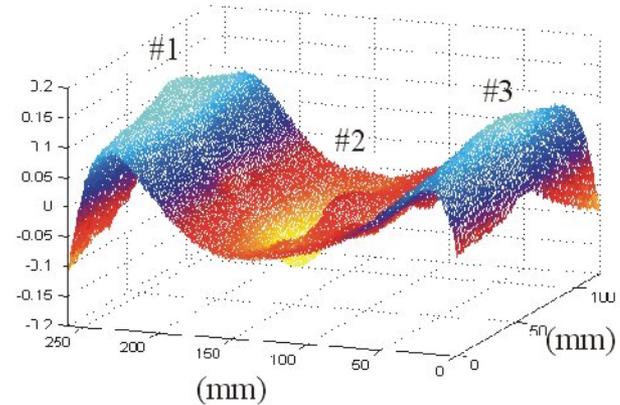
b) Face B without open notches



c) Face A with open notches
after removing the shift in (a)

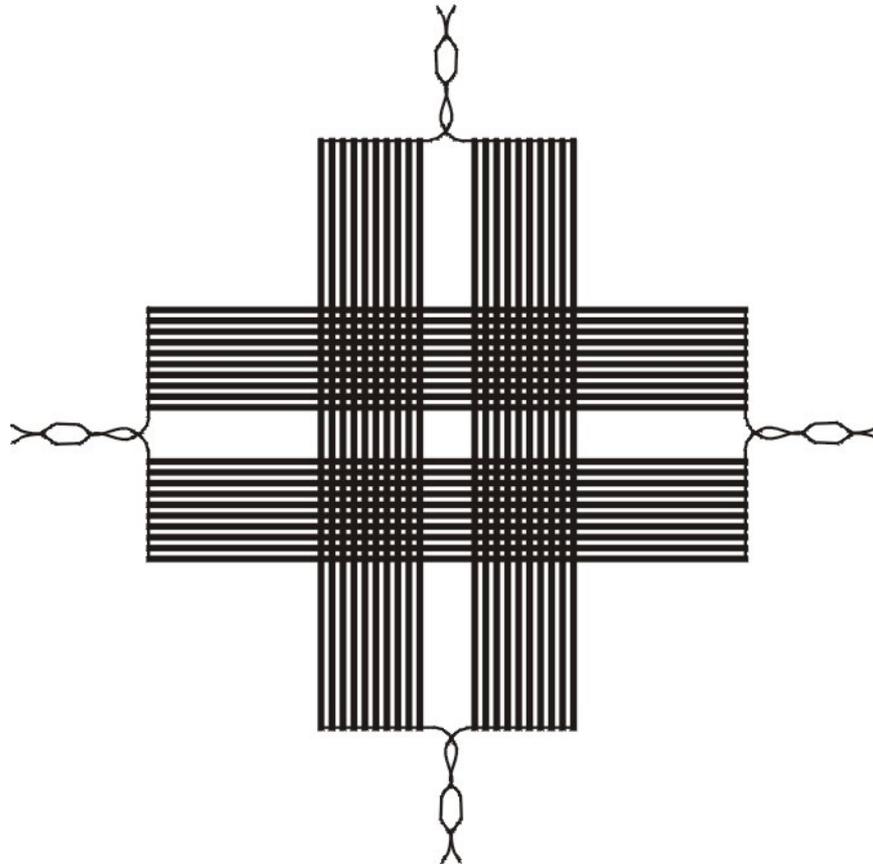


d) Face B without open notches
after removing the shift in (b)





PC Orthogonal Sheet Inducer





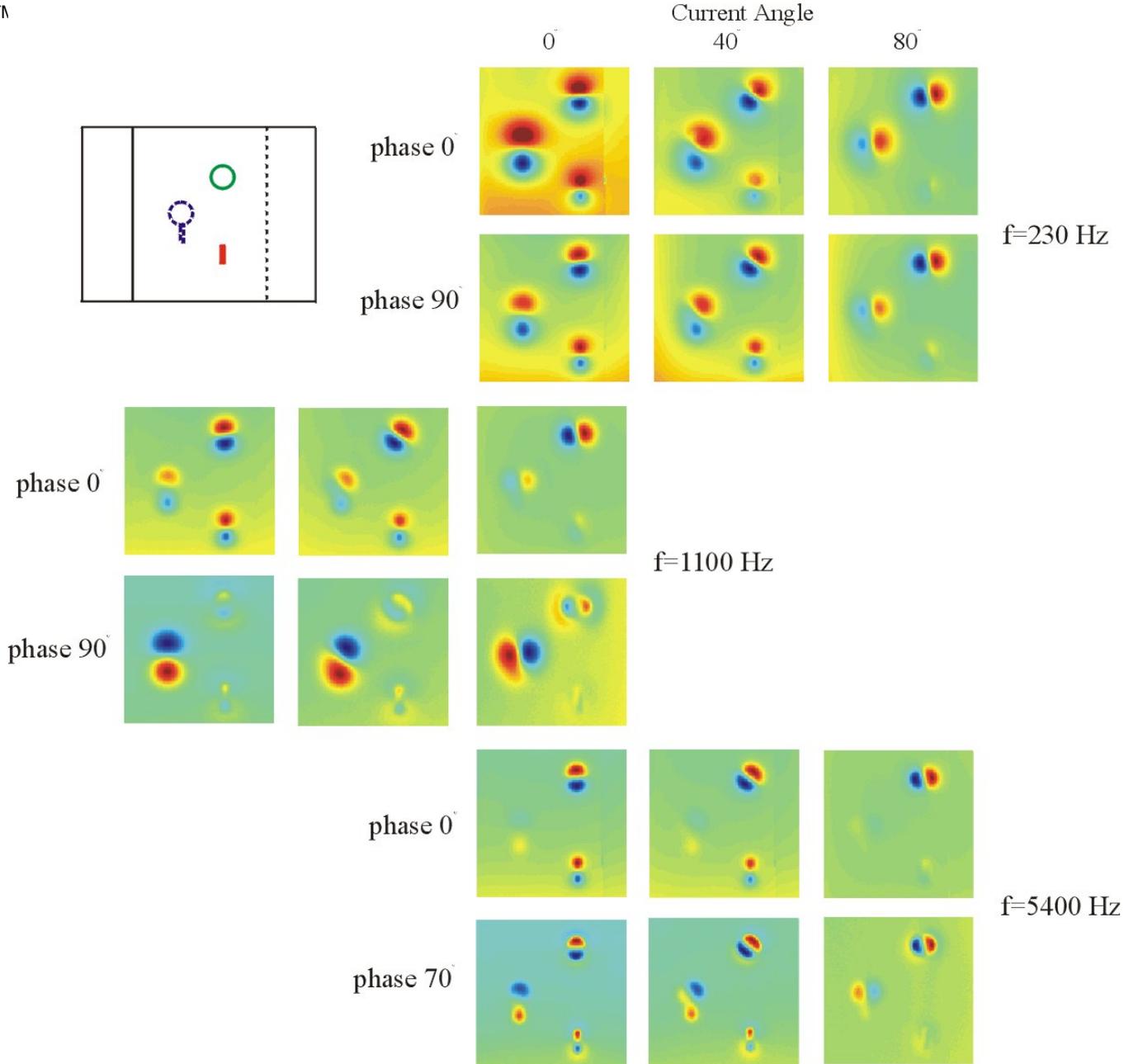
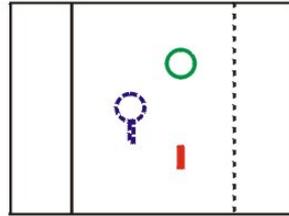
FREQUENCY OPTIMIZATION

for phase-selection



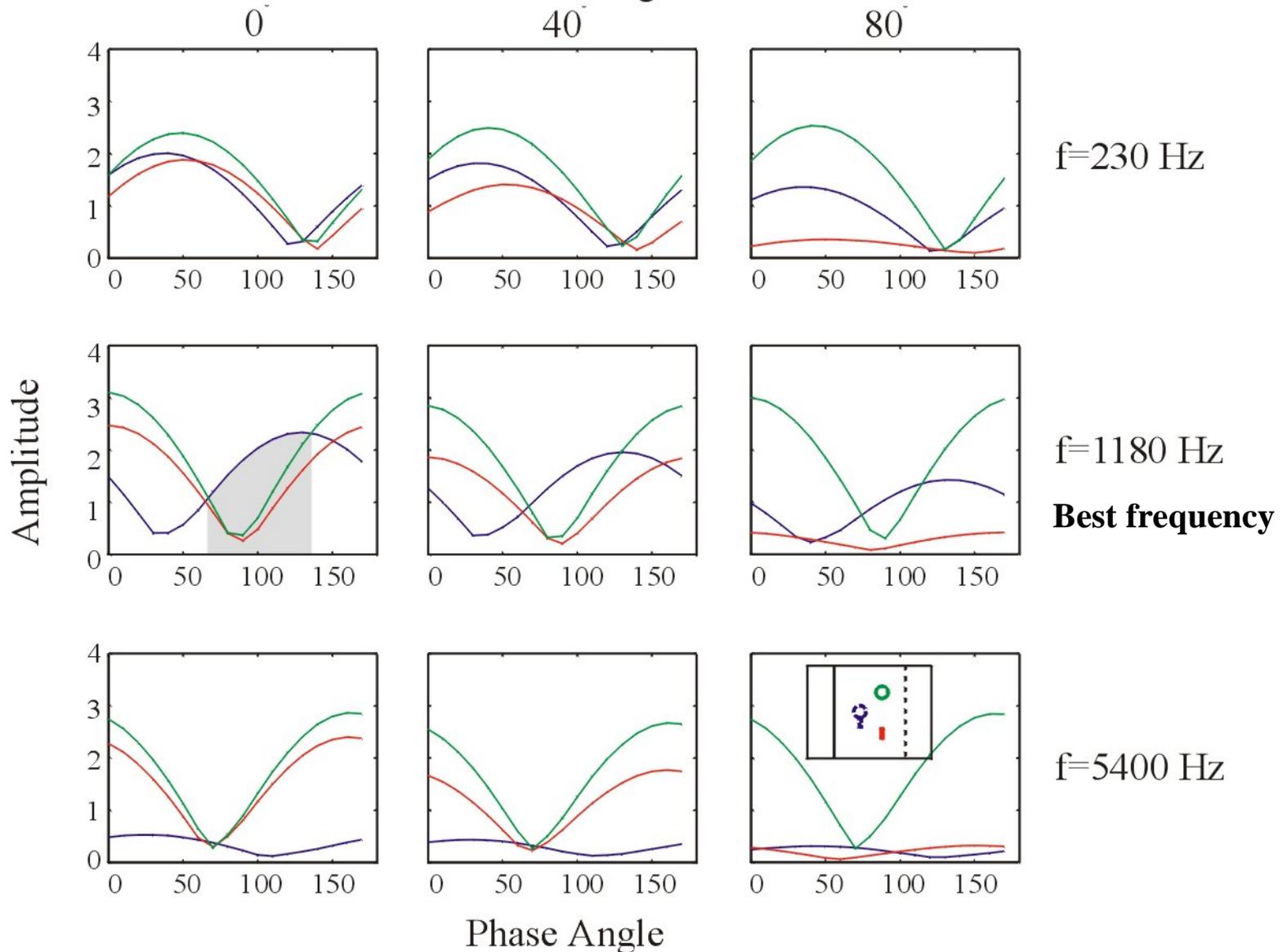
ELECTROMAGNETICS LABORATORY

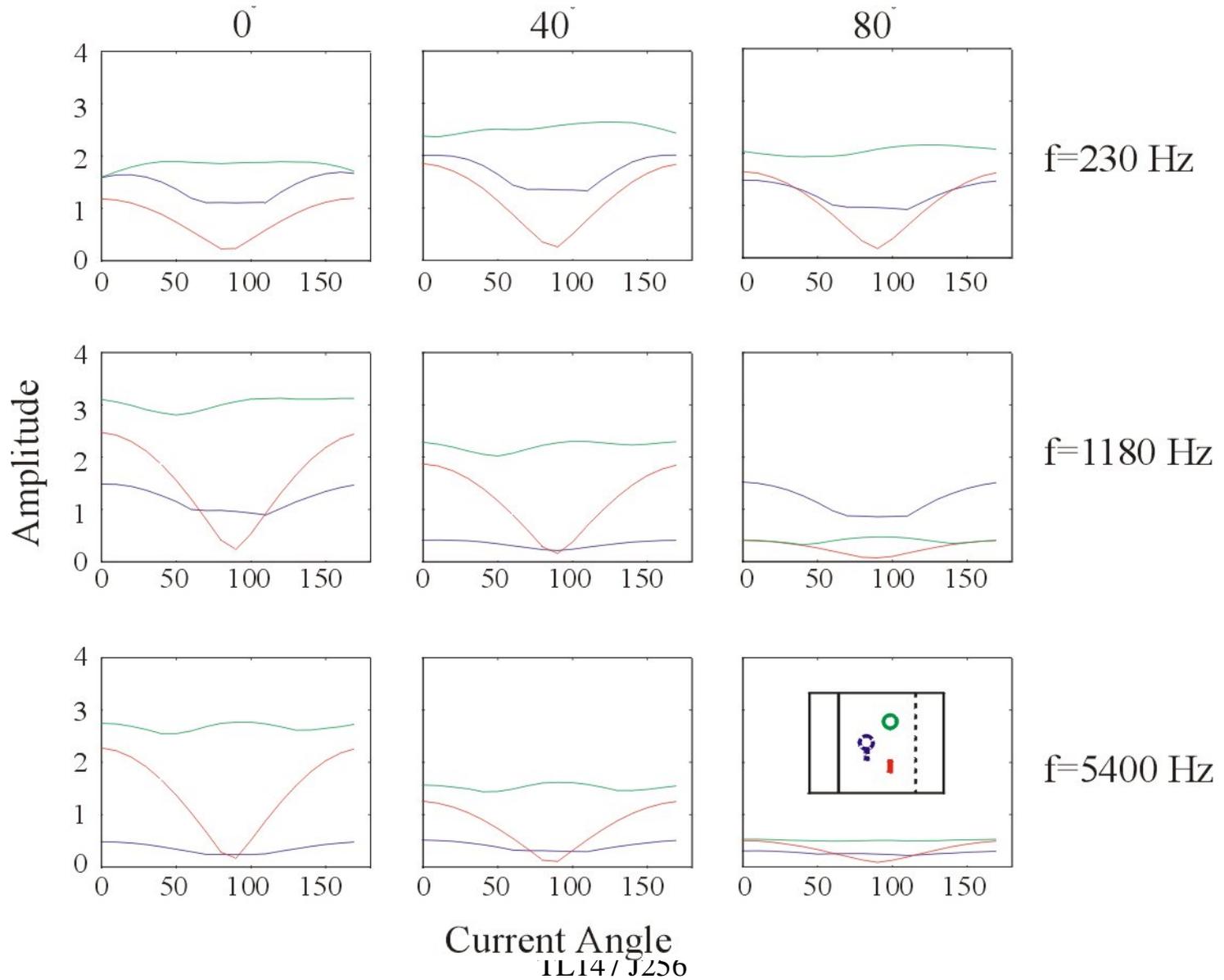
DEPARTM





Current Angle



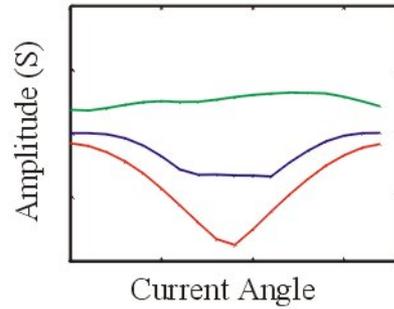




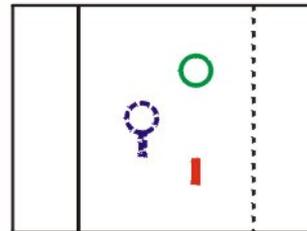
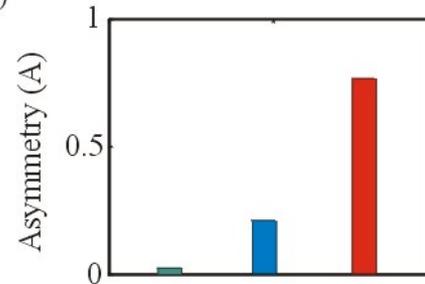
Self-referencing

Phase Angle 40
 $f=230$ Hz

a)

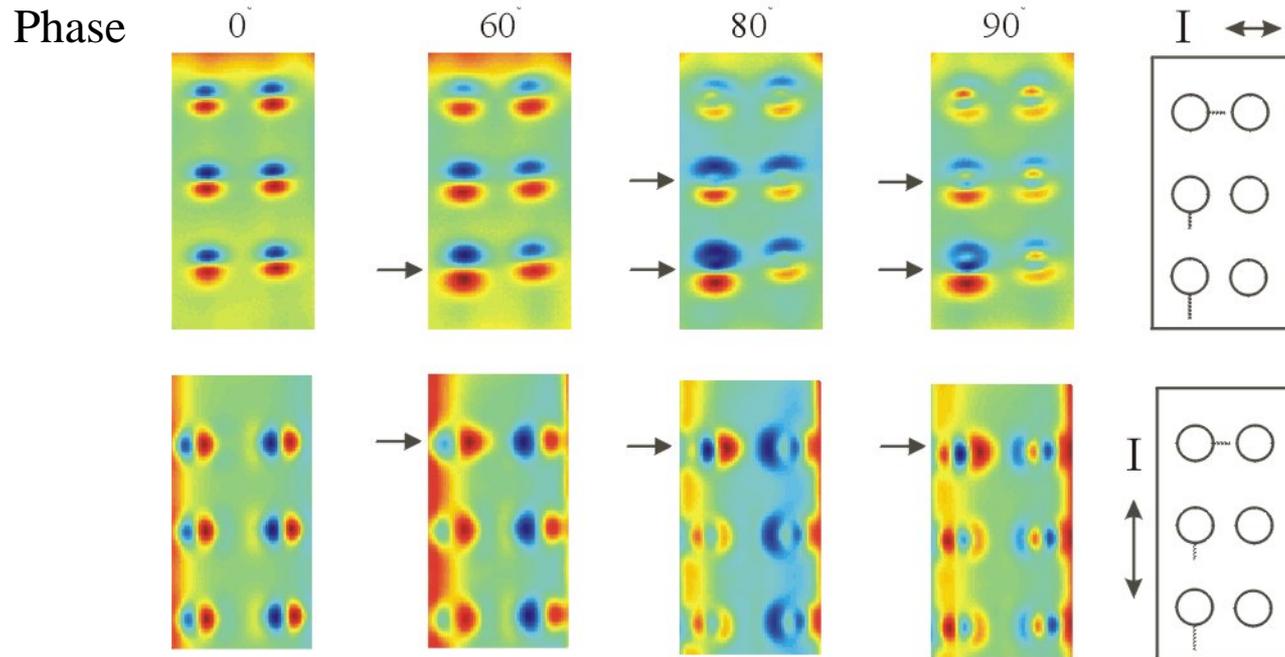
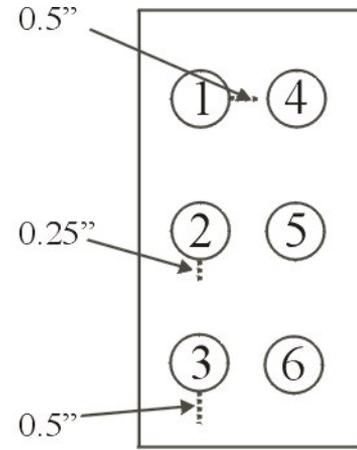


b)





Second Layer slots

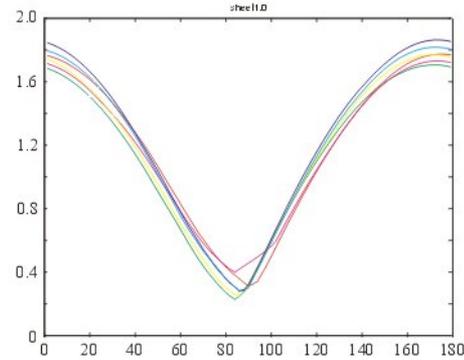




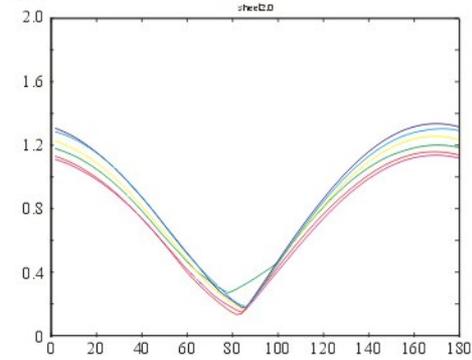
Phase Analysis



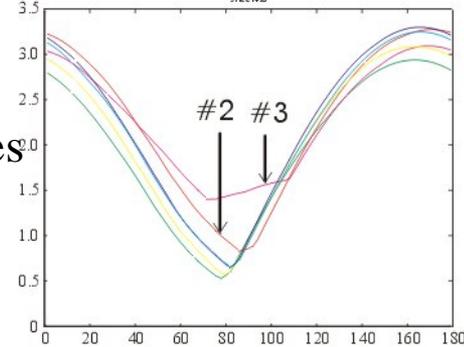
(a) 1010 Hz (transverse current)



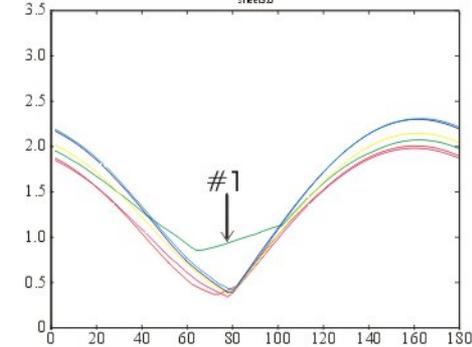
(b) 1010 Hz (longitudinal current)



(c) 570 Hz (transverse current)

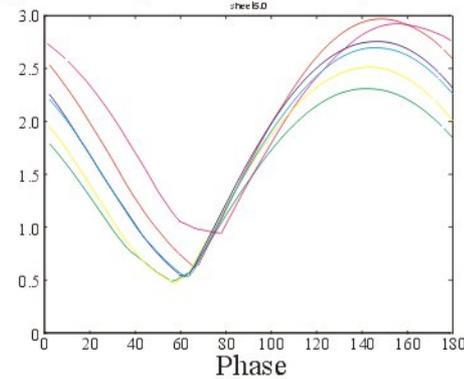


(d) 570 Hz (longitudinal current)

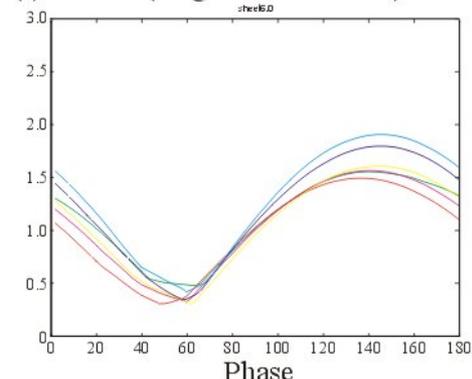


Better frequencies
570 Hz - 1 kHz

(e) 370 Hz (transverse current)

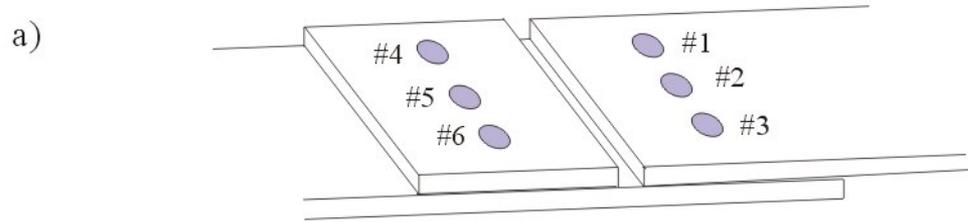


(f) 370 Hz (longitudinal current)

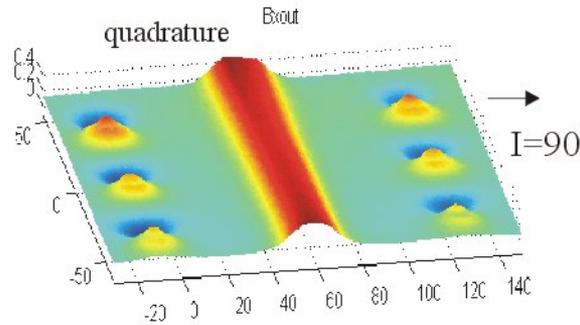
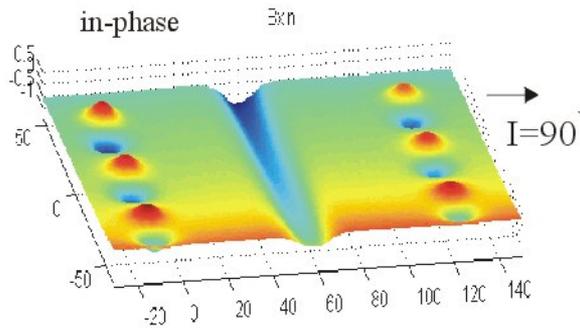




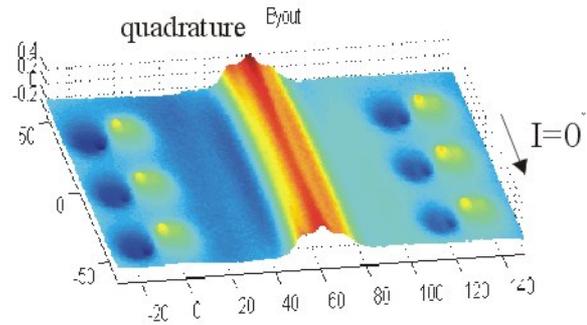
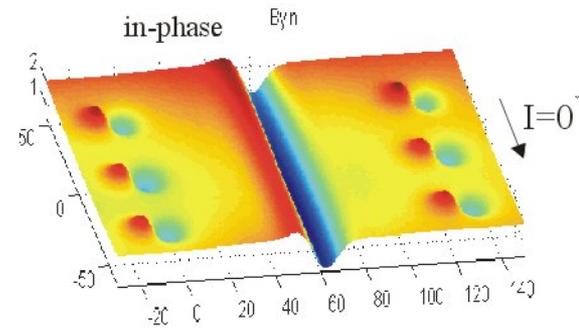
FATIGUE CRACKS SAMPLE



b) Longitudinal current

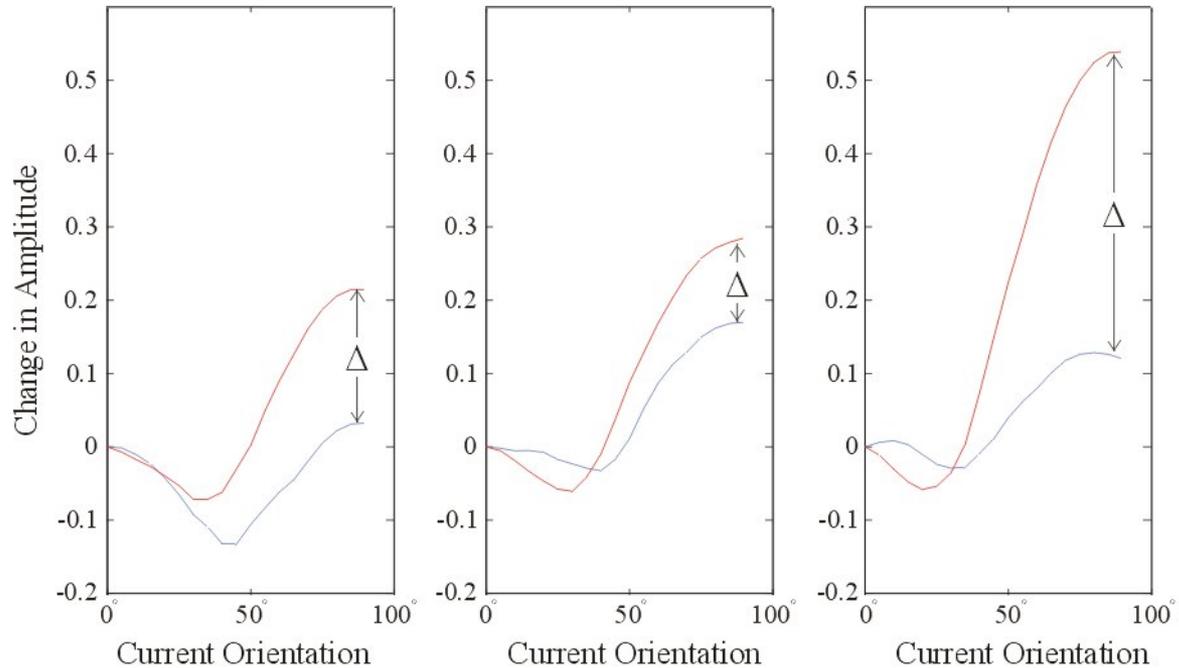
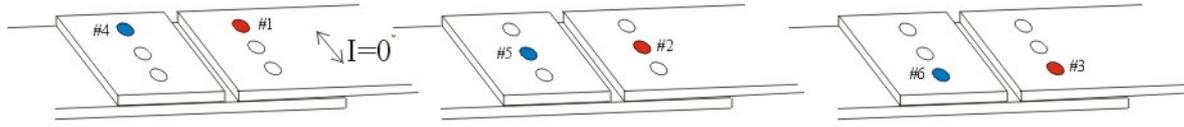


c) Transverse current





DETECTION FOR FATIGUE CRACKS BENEATH RIVETS

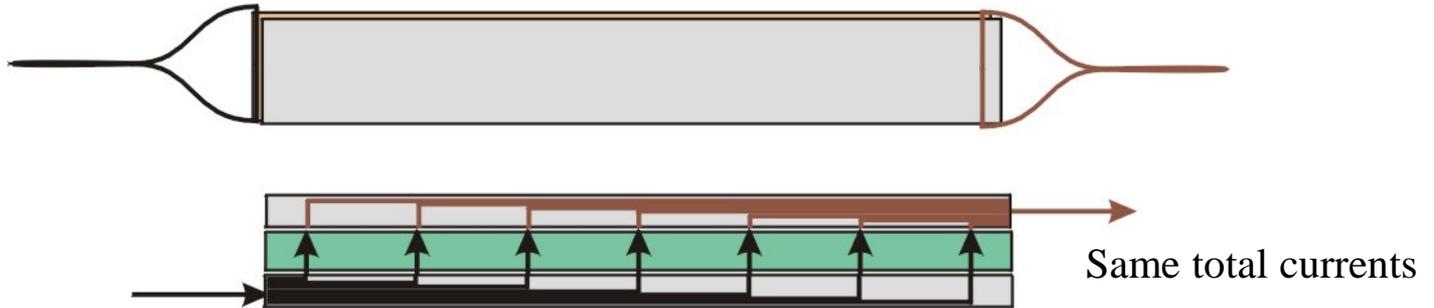


Total length of crack: #1 --- 4.41mm, #2 --- 3.53mm, #3 --- 4.66mm

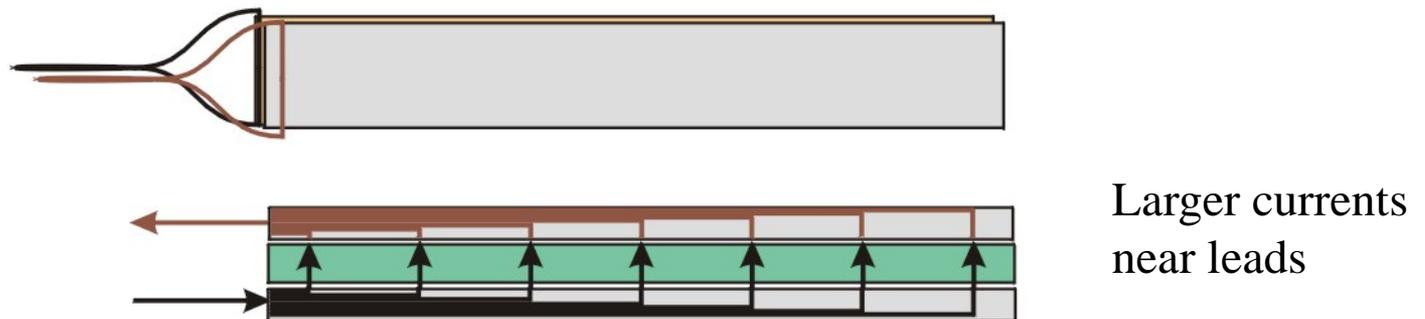


ALUMINUM CAPACITOR

a) Different end leads connection



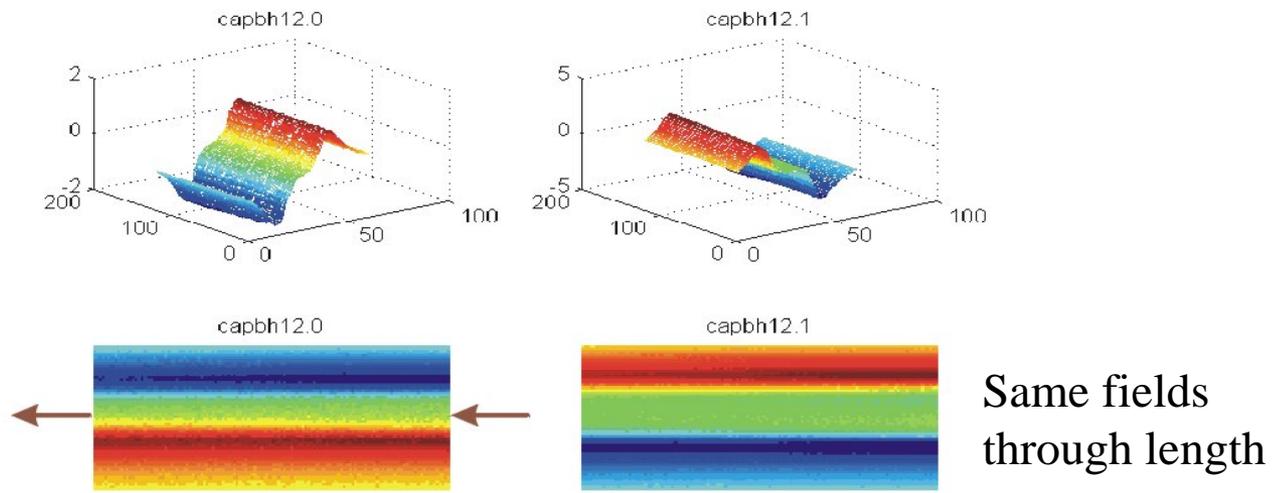
b) Same end leads connection



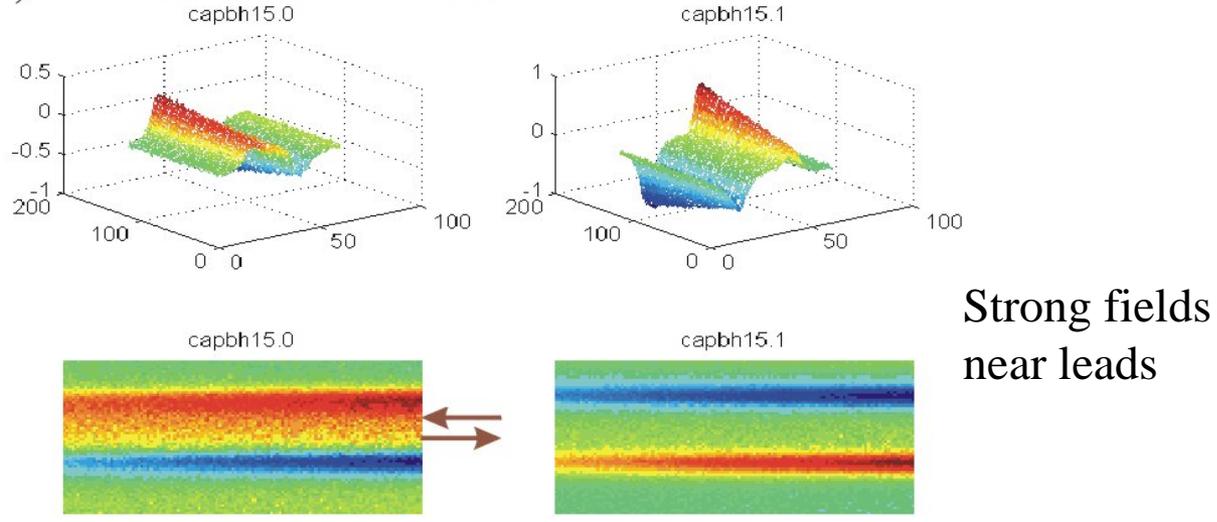


FIELD MAP FOR ALUMINUM CAPACITOR (G-10 layer has a hole, 2kHz)

a) Different end leads connection



b) Same end leads connection





(a) G-10 layer has a copper disk



(b) Image of a 3/4 inch diameter copper disk



(c) Image of a 3/8 inch diameter copper disk





Displacement currents are collected by leads through aluminum.

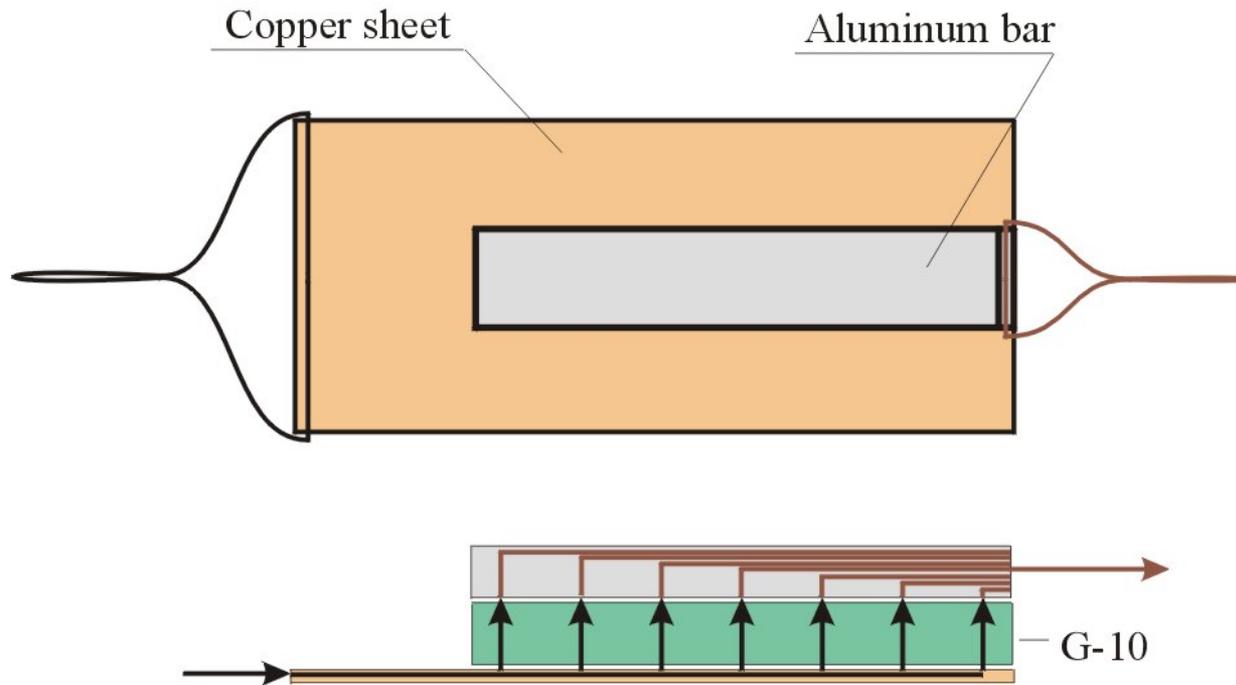
Magnetic fields (B_z) is mainly due to the collected currents.

How to increase the feasibility of displacement current distribution??

----Reduce cancellation between two electrodes



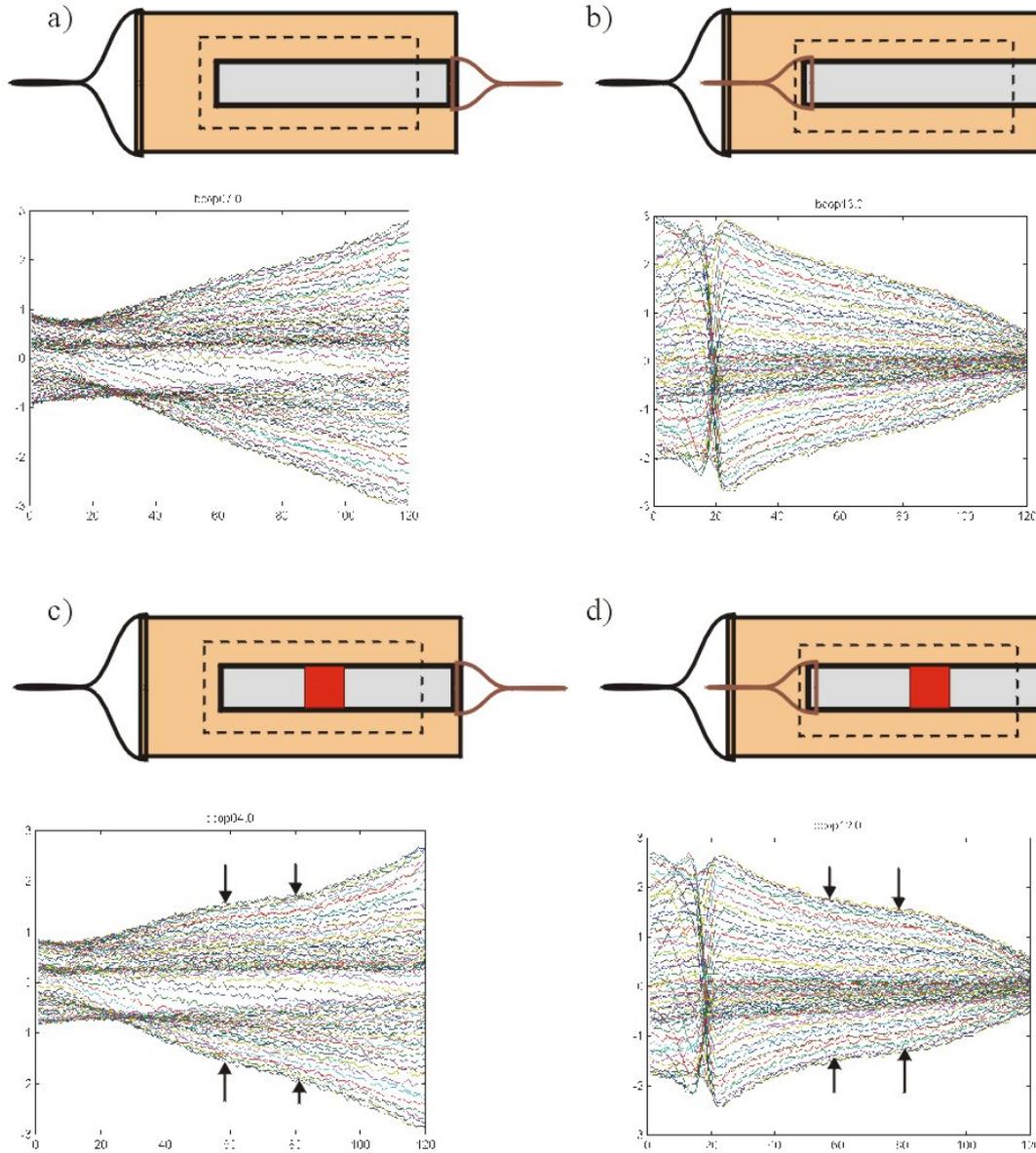
COPPER - ALUMINUM CAPACITOR





ELECTROMAGNETICS LABORATORY

DEPARTMENT OF
MAGNETIC FIELD OF CAPACITOR





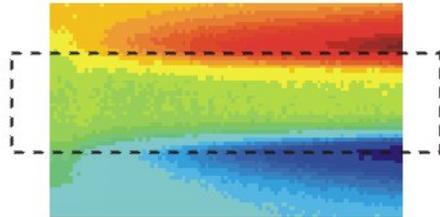
Unflawed G-10



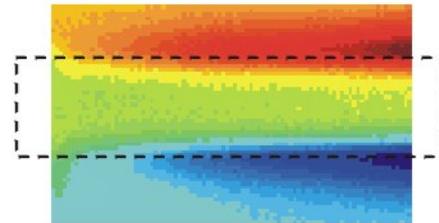
Flawed G-10



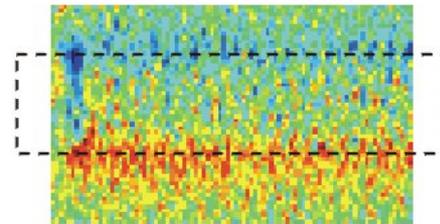
a) Raw data



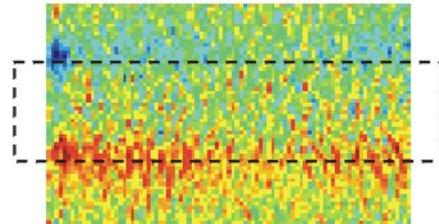
b) Raw data



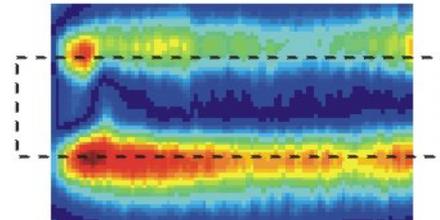
c) Derivative filtering



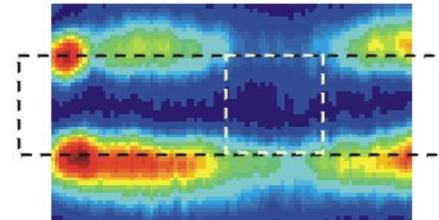
d) Derivative filtering



e) Low pass filtering



f) Low pass filtering

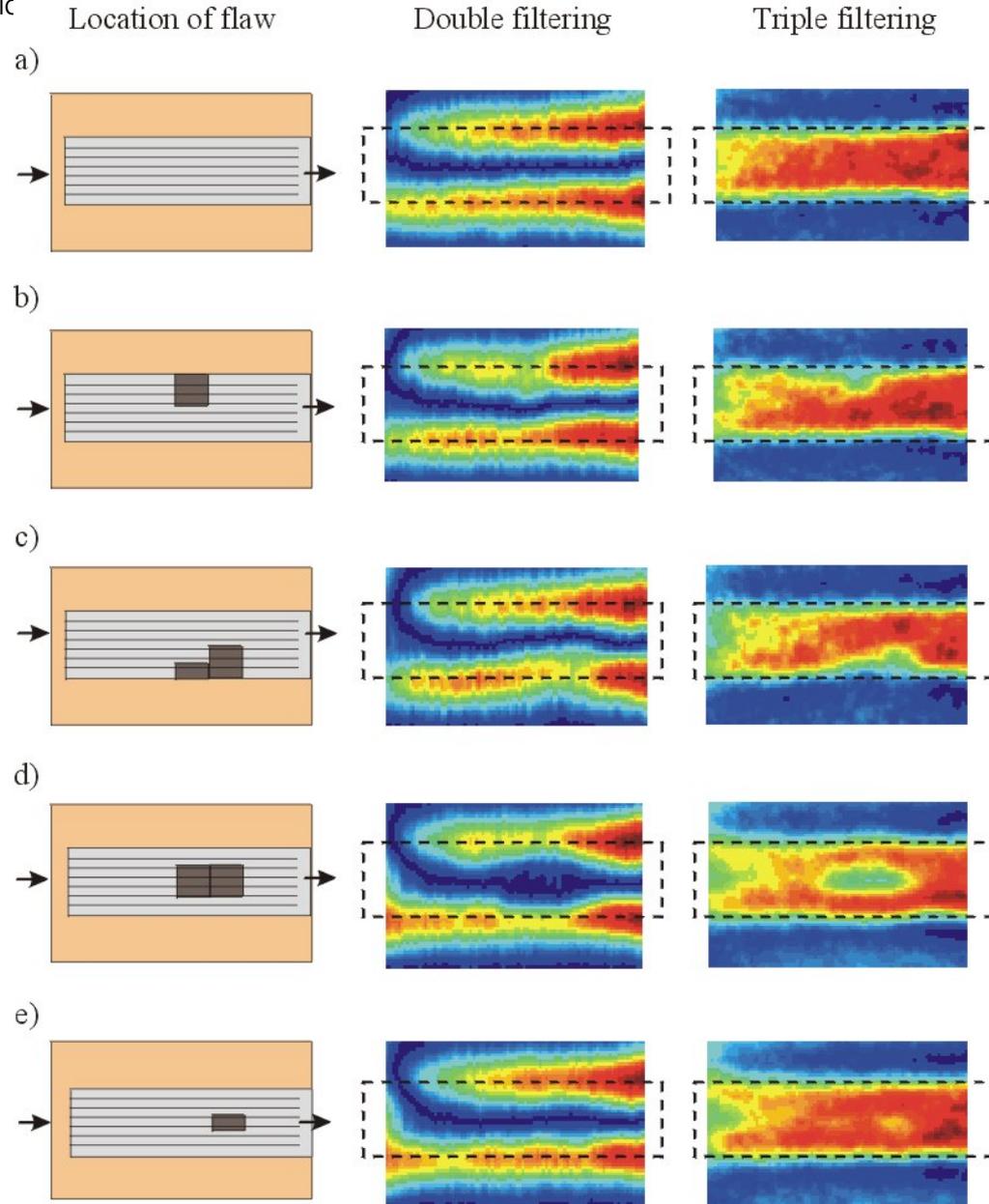




INCREASE EDGES !!!



COPPER - SLOTTED ALUMINUM CAPACITOR

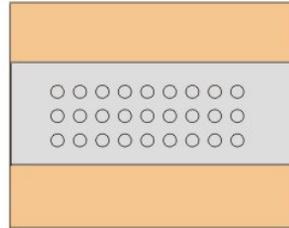




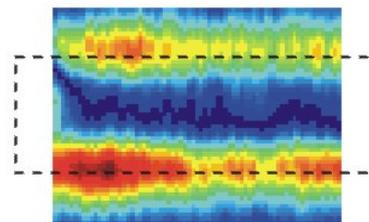
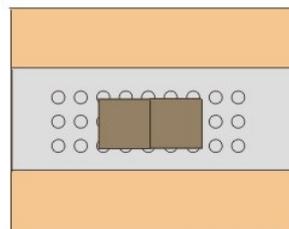
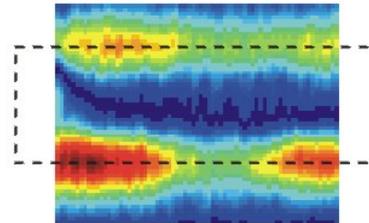
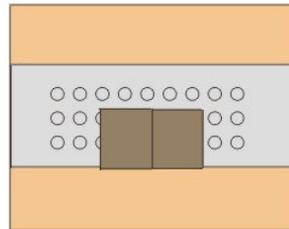
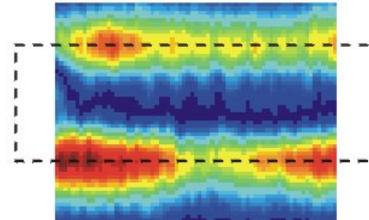
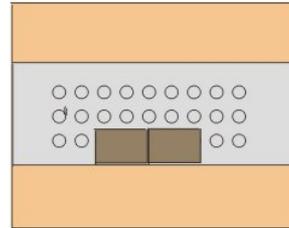
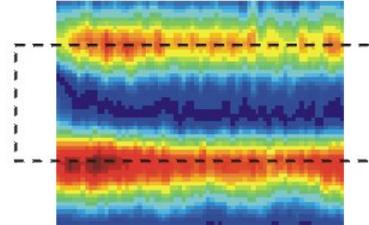
ELECTROMAGNETIC COPPER - MULT HOLE ALUMINUM CAPACITOR

DEPARTMENT OF PHYSICS A

Location of the flaw

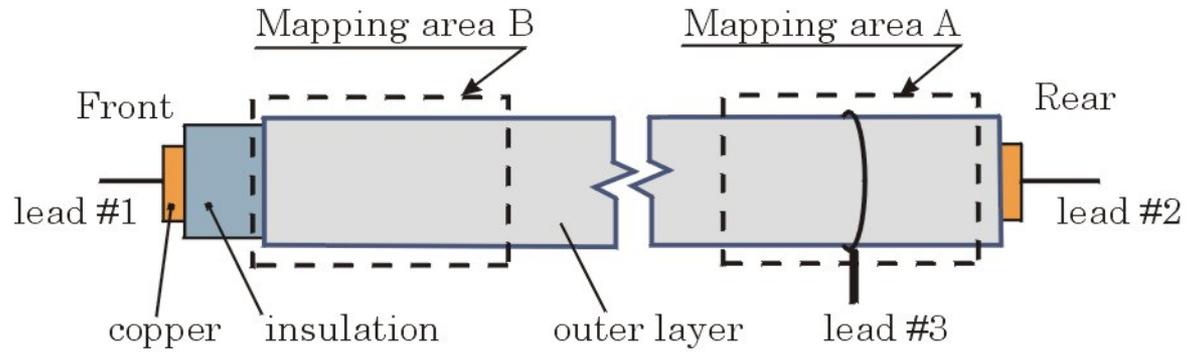


Double filtering

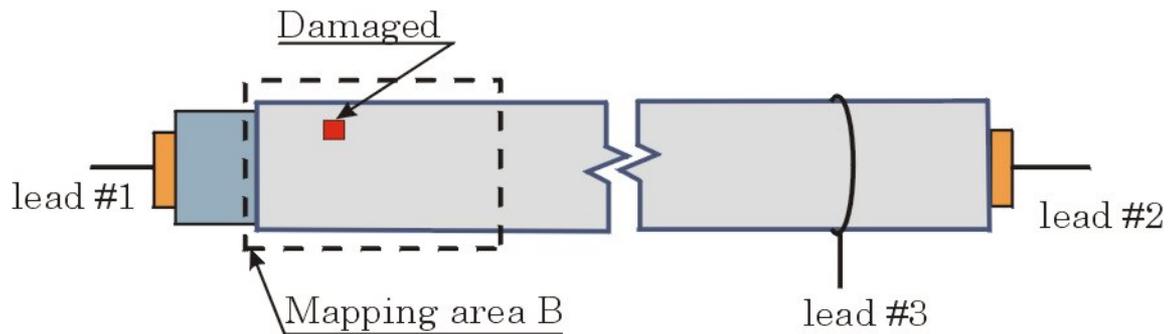


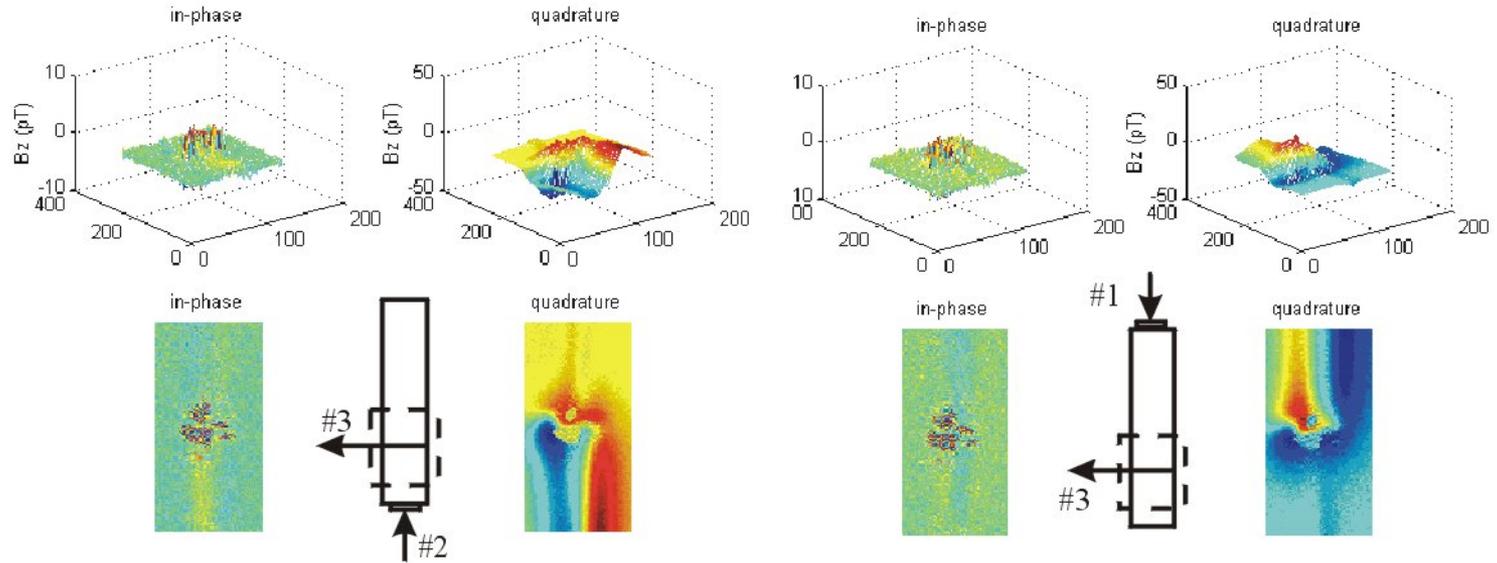


UNFLAWED BAR

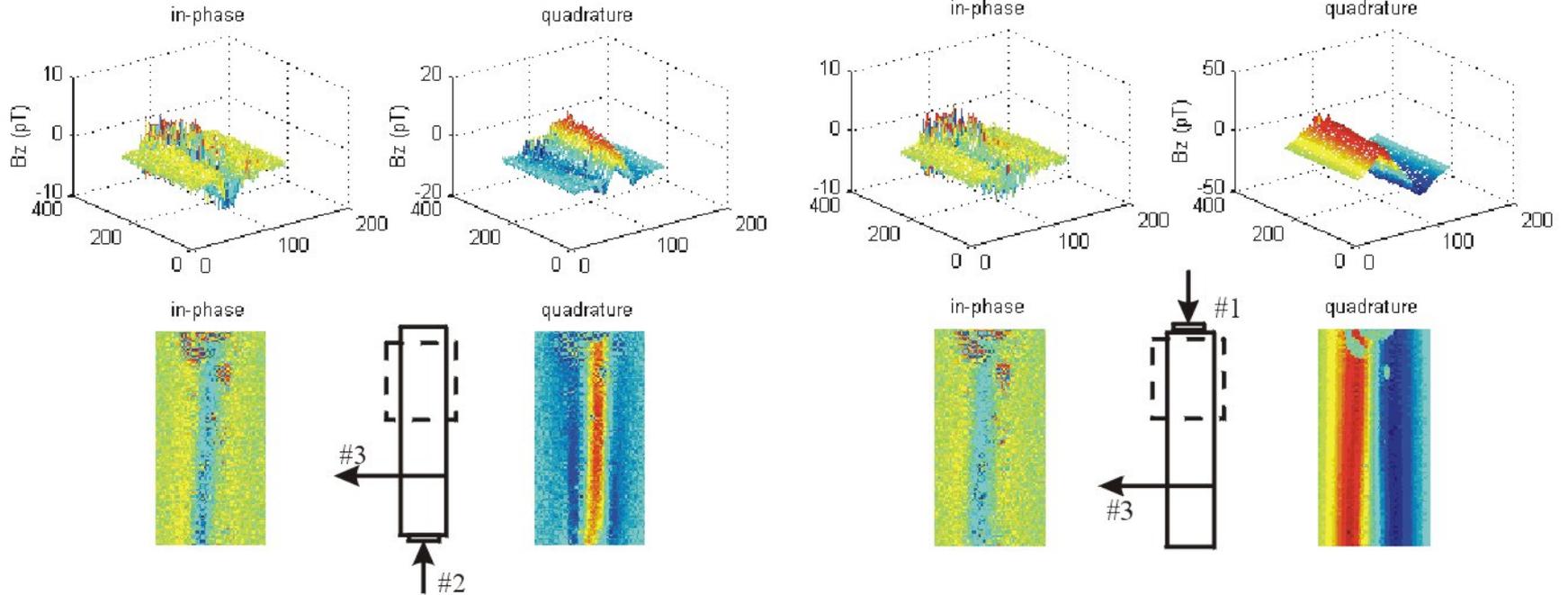


FLAWED BAR

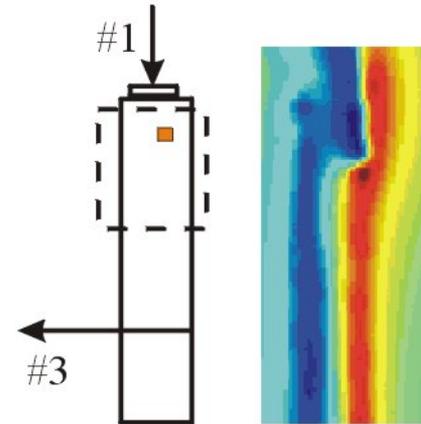
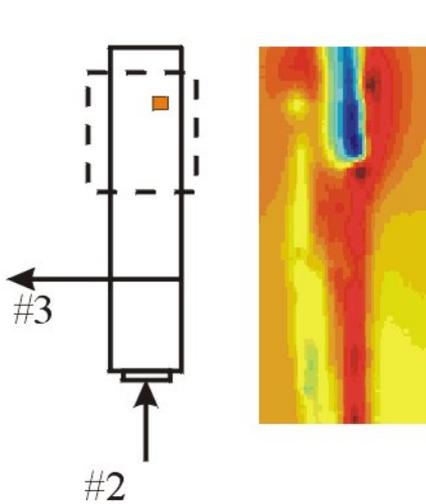
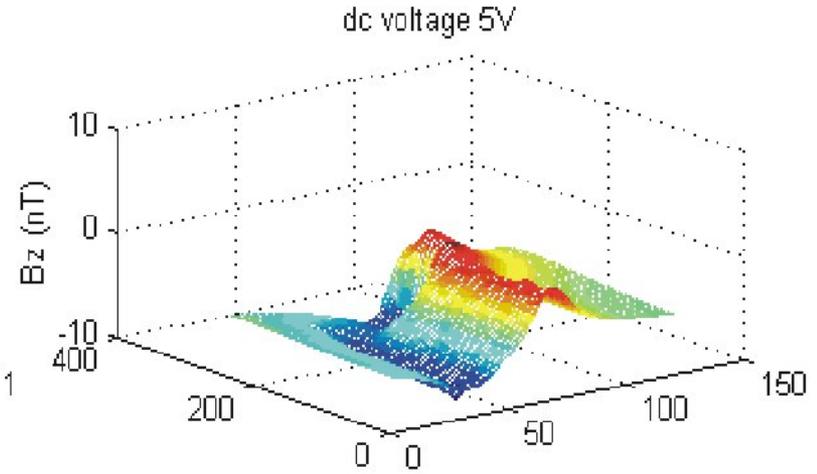
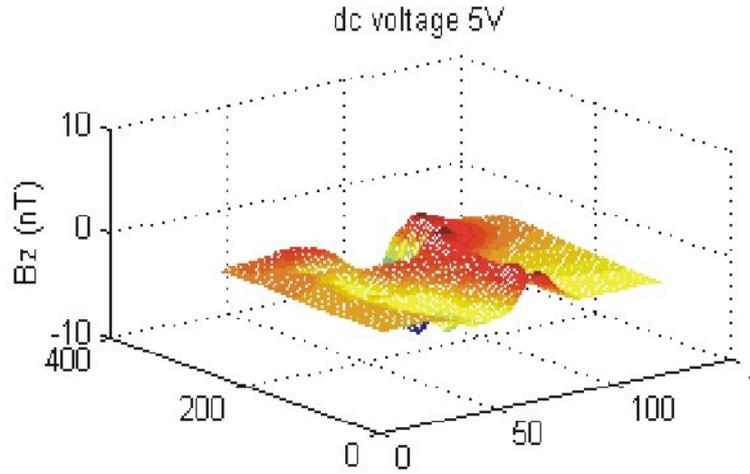




Unflawed bar
10V 200 Hz voltage



Unflawed bar
10V 200 Hz voltage



Flawed bar with breakage
5V dc voltage
TL147 J256